



GPR25L081B

8M-BIT [x1 / x2] CMOS SERIAL FLASH

DEC. 15, 2010

Version 1.1

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8M-BIT [x 1/ x 2] CMOS SERIAL FLASH

1. FEATURES

1.1. General

- Single Power Supply Operation
 - 2.7 to 3.6 volt for read, erase, and program operations
- Serial Peripheral Interface compatible -- Mode 0 and Mode 3
- 8,388,608 x 1 bit structure or 4,194,304 x 2 bits (Dual Output mode) structure
- 256 Equal Sectors with 4K byte each
 - Any Sector can be erased individually
- 16 Equal Blocks with 64K byte each
 - Any Block can be erased individually
- Program Capability
 - Byte base
 - Page base (256 bytes)
- Latch-up protected to 100mA from -1V to $V_{CC} + 1V$
- GPR25L081B is compatible with MX25L8006E

1.2. Performance

- High Performance
 - Fast access time: 86MHz serial clock
 - Serial clock of Dual Output mode : 80MHz
 - Fast program time: 1.4ms(typ.) and 5ms(max.)/page
 - Byte program time: 9us (typical)
 - Fast erase time: 60ms(typ.) /sector ; 0.7s(typ.) /block
- Low Power Consumption
 - Low active read current: 12mA(max.) at 86MHz
 - Low active programming current: 20mA (max.)
 - Low active erase current: 20mA (max.)
 - Low standby current: 50uA (max.)

- Deep power-down mode 5uA (typical)
- Typical 100,000 erase/program cycles
- 20 years of data retention

1.3. Software Features

- Input Data Format
 - 1-byte Command code
- Advanced Security Features
 - Block lock protection
 - BP2-BP0 status bit defines the size of the area to be software protection against program and erase instructions
 - Additional 512 bit secured OTP for unique identifier
- Auto Erase and Auto Program Algorithm
 - Automatically erases and verifies data at selected sector
 - Automatically programs and verifies data at selected page by an internal algorithm that automatically times the program pulse widths (Any page to be programmed should have page in the erased state first)
- Status Register Feature
- Electronic Identification
 - JEDEC 1-byte manufacturer ID and 2-byte device ID
 - RES command for 1-byte Device ID
 - REMS commands for 1-byte manufacturer ID and 1-byte device ID
- Support Discoverable Memory Capabilities (DMC) Signature

1.4. Hardware Features

- PACKAGE
 - 8-pin SOP (150mil)

2. GENERAL DESCRIPTION

The device features a serial peripheral interface and software protocol allowing operation on a simple 3-wire bus. The three bus signals are a clock input (SCLK), a serial data input (SI), and a serial data output (SO). Serial access to the device is enabled by CS# input.

When it is in Dual Output read mode, the SI pin and SO pin become SIO0 pin for data output.

The device provides sequential read operation on whole chip.

After program/erase command is issued, auto program/ erase algorithms which program/ erase and verify the specified page or sector/block locations will be executed. Program command is executed on byte basis, or page basis, or word basis for Continuously program mode, and erase command is executes on sector, or block, or whole chip basis.

To provide user with ease of interface, a status register is included to indicate the status of the chip. The status read command can be issued to detect completion status of a program or erase operation via WIP bit.

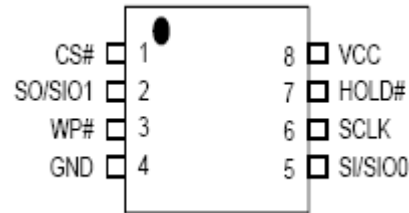
Advanced security features enhance the protection and security functions, please see security features section for more details.

When the device is not in operation and CS# is high, it is put in standby mode.

The GPR25L081B reliably stores memory contents even after typical 100,000 program and erase cycles.

3. PIN CONFIGURATIONS

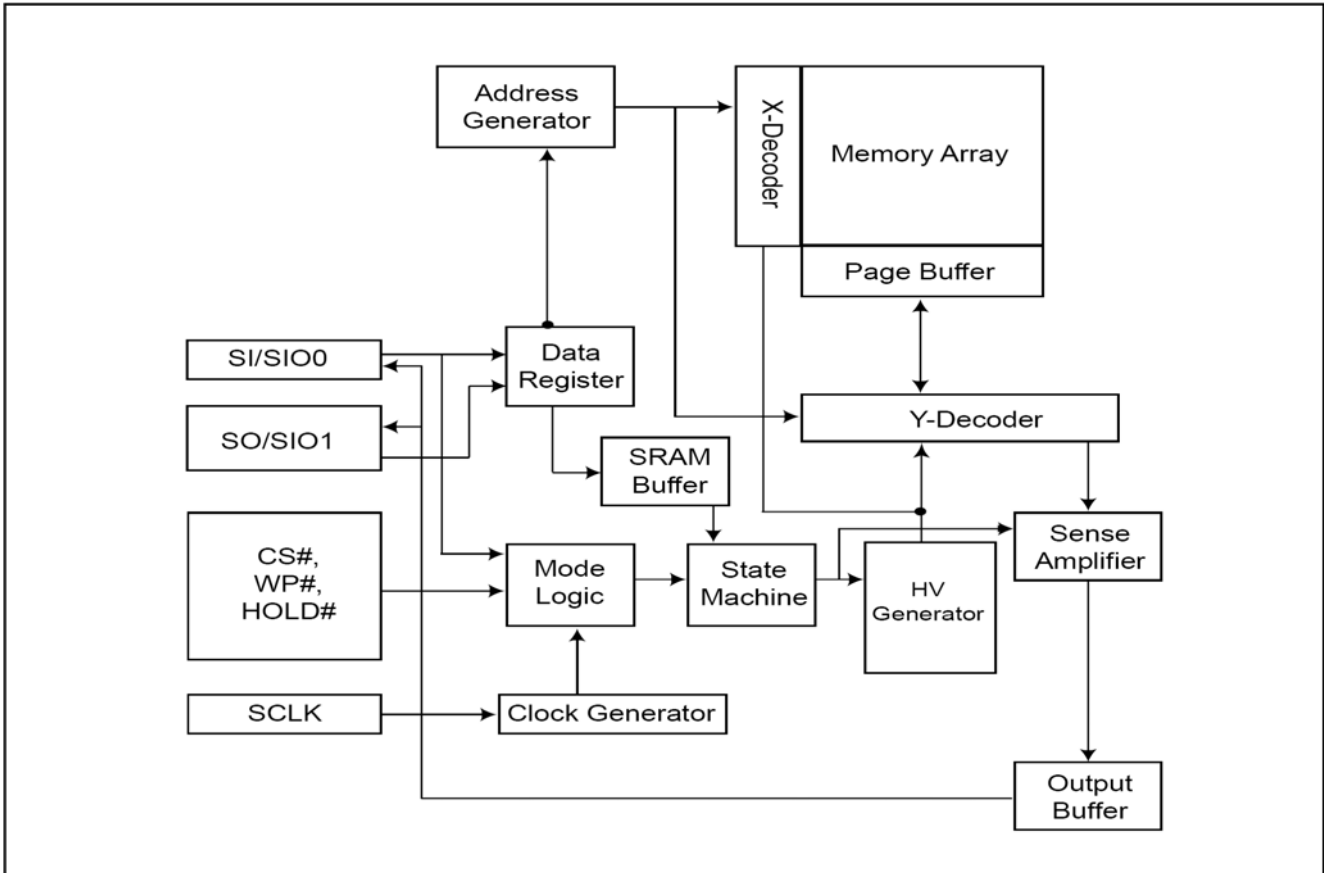
3.1. 8-PIN SOP (150mil)



4. PIN DESCRIPTION

Symbol	Description
CS#	Chip Select
SI/SIO0	Serial Data Input (for 1 x I/O)/ Serial Data Input & Output (for Dual Output mode)
SO/SIO1	Serial Data Output (for 1 x I/O)/ Serial Data Output (for Dual Output mode)
SCLK	Clock Input
WP#	Write protection
HOLD#	Hold, to pause the device without deselecting the device
VCC	Power Supply
GND	Ground

5. BLOCK DIAGRAM



6. MEMORY ORGANIZATION

Table 1. Memory Organization

Block	Sector	Address Range	
		Start	End
15	255	0FF000h	0FFFFFh
	:	:	:
	240	0F0000h	0F0FFFh
14	239	0EF000h	0EFFFFh
	:	:	:
	224	0E0000h	0E0FFFh
:	:	:	:
:	:	:	:
0	15	00F000h	00FFFFh
	:	:	:
	3	003000h	003FFFh
	2	002000h	002FFFh
	1	001000h	001FFFh
	0	000000h	000FFFh

7. DEVICE OPERATION

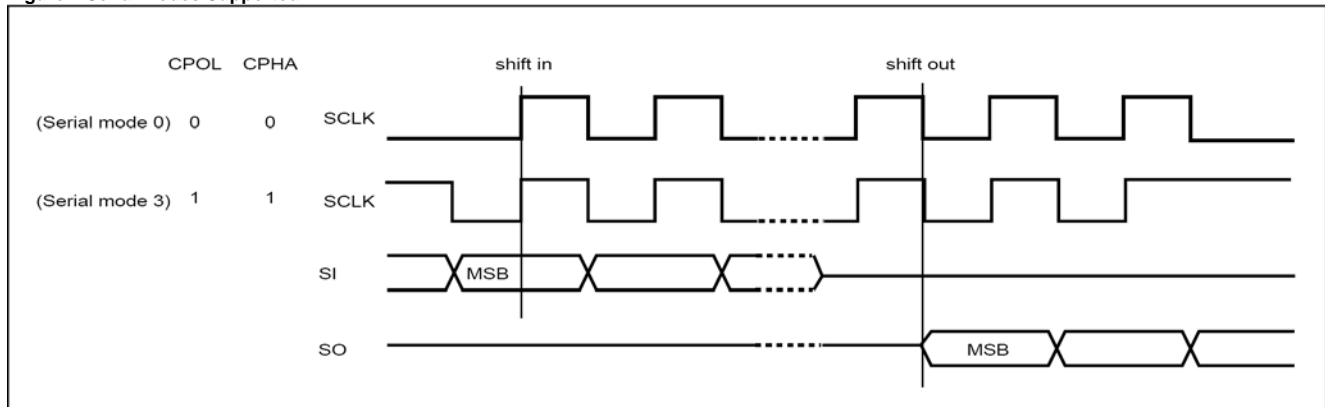
1. Before a command is issued, status register should be checked to ensure device is ready for the intended operation.
2. When incorrect command is inputted to this LSI, this LSI becomes standby mode and keeps the standby mode until next CS# falling edge. In standby mode, SO pin of this LSI should be High-Z.
3. When correct command is inputted to this LSI, this LSI becomes active mode and keeps the active mode until next CS# rising edge.
4. Input data is latched on the rising edge of Serial Clock(SCLK) and data shifts out on the falling edge of SCLK. The difference of

Serial mode 0 and mode 3 is shown in Figure 1.

5. For the following instructions: RDID, RDSR, RDSCUR, READ, FAST_READ, DREAD, RES, REMS and RDDMC the shifted-in instruction sequence is followed by a data-out sequence. After any bit of data being shifted out, the CS# can be high. For the following instructions: WREN, WRDI, WRSR, SE, BE, CE, PP, RDP, DP, ENSO, EXSO, and WRSCUR, the CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed.

6. During the progress of Write Status Register, Program, Erase operation, to access the memory array is neglected and not affect the current operation of Write Status Register, Program, Erase.

Figure1. Serial Modes Supported



Note: CPOL indicates clock polarity of Serial master, CPOL=1 for SCLK high while idle, CPOL=0 for SCLK low while not transmitting. CPHA indicates clock phase. The combination of CPOL bit and CPHA bit decides which Serial mode is supported.

8. DATA PROTECTION

The GPR25L081B is designed to offer protection against accidental erasure or programming caused by spurious system level signals that may exist during power transition. During power up the device automatically resets the state machine in the standby mode. In addition, with its control register architecture, alteration of the memory contents only occurs after successful completion of specific command sequences. The device also incorporates several features to prevent inadvertent write cycles resulting from VCC power-up and power-down transition or system noise.

- Valid command length checking: The command length will be checked whether it is at byte base and completed on byte boundary.
- Write Enable (WREN) command: WREN command is required to set the Write Enable Latch bit (WEL) before other command to change data. The WEL bit will return to reset stage under following situation:
 - Power-up
 - Write Disable (WRDI) command completion
 - Write Status Register (WRSR) command completion
 - Page Program (PP) command completion
 - Sector Erase (SE) command completion

- Block Erase (BE) command completion
- Chip Erase (CE) command completion
- Deep Power Down Mode: By entering deep power down mode, the flash device also is under protected from writing all commands except Release from deep power down mode command (RDP) and Read Electronic Signature command (RES).
- Advanced Security Features: there are some protection and security features which protect content from inadvertent write and hostile access.

I. Block lock protection

- The Software Protected Mode (SPM):
Use (BP2, BP1, BP0) bits to allow part of memory to be protected as read only. The protected area definition is shown as table of "Protected Area Sizes", the protected areas are more flexible which may protect various area by setting value of BP0-BP2 bits.
Please refer to table of "protected area sizes".
- The Hardware Protected Mode (HPM) uses WP# to protect the BP2-BP0 bits and SRWD bit.

Table2. Protected Area Sizes

Status bit			Protect Level
BP2	BP1	BP0	
0	0	0	0 (none)
0	0	1	1 (1block, block 15th)
0	1	0	2 (2blocks, block 14th-15th)
0	1	1	3 (3blocks, block 12th-15th)
1	0	0	4 (4blocks, block 8th-15th)
1	0	1	5 (All)
1	1	0	6 (All)
1	1	1	7 (All)

II. Additional 512 bit secured OTP for unique identifier: to provide 512 bit one-time program area for setting device unique serial number - Which may be set by factory or system customer. please refer to table 3. 512 bit secured OTP definition.

- Security register bit 0 indicates whether the chip is locked by factory or not.
- To program the 512 bit secured OTP by entering 512 bit secured OTP mode (with ENSO command), and going through normal program procedure, and then exiting 512 bit secured OTP mode by writing EXSO command.

- Customer may lock-down the customer lockable secured OTP by writing WRSCUR(write security register) command to set customer lock-down bit1 as "1". Please refer to table of "security register definition" for security register bit definition and table of "512 bit secured OTP definition" for address range definition.
- **Note:** Once lock-down whatever by factory or customer, it cannot be changed any more. While in 512 bit secured OTP mode, array access is not allowed.

Table3. 512 bit Secured OTP Definition

Address range	Size	Standard Factory Lock	Customer Lock
xxxx00~xxxx0F	128-bit	ESN (electrical serial number)	Determined by customer
xxxx10~xxxx3F	384-bit	N/A	

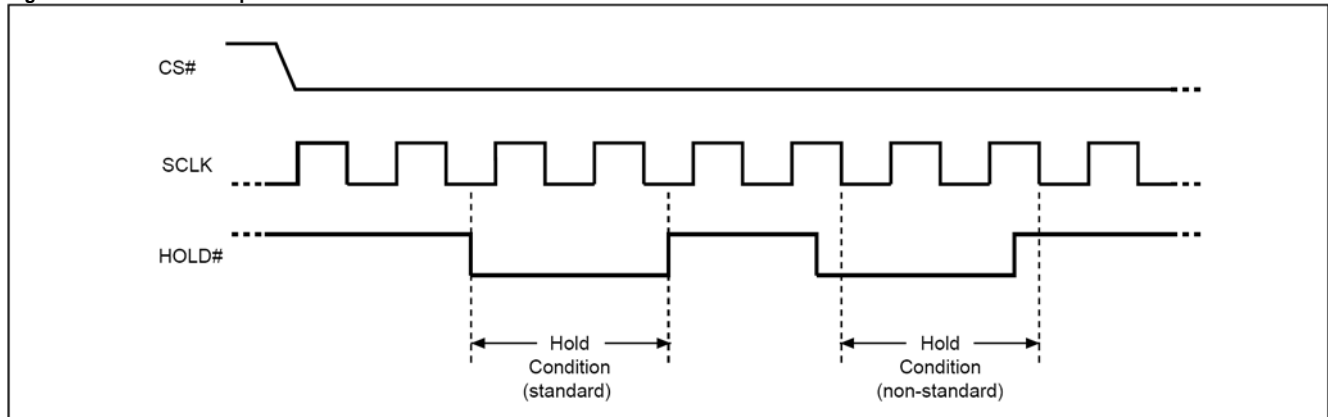
9. HOLD FEATURE

HOLD# pin signal goes low to hold any serial communications with the device. The HOLD feature will not stop the operation of write status register, programming, or erasing in progress.

The operation of HOLD requires Chip Select(CS#) keeping low and starts on falling edge of HOLD# pin signal while Serial Clock

(SCLK) signal is being low (if Serial Clock signal is not being low, HOLD operation will not start until Serial Clock signal being low). The HOLD condition ends on the rising edge of HOLD# pin signal while Serial Clock(SCLK) signal is being low(if Serial Clock signal is not being low, HOLD operation will not end until Serial Clock being low), see Figure 1.

Figure1. Hold Condition Operation



The Serial Data Output (SO) is high impedance, both Serial Data Input (SI) and Serial Clock (SCLK) are don't care during the HOLD operation. If Chip Select (CS#) drives high during HOLD

operation, it will reset the internal logic of the device. To re-start communication with chip, the HOLD# must be at high and CS# must be at low.

10. COMMAND DESCRIPTION

Table4. Command Definition

Command (byte)	WREN (write enable)	WRDI (write disable)	RDSR (read status register)	WRSR (write status register)	READ (read data)	FAST READ (fast read data)	DREAD (Double Output Mode command)
1st byte	06 (hex)	04 (hex)	05 (hex)	01 (hex)	03 (hex)	0B (hex)	3B (hex)
2nd byte	-	-	-	-	AD1	AD1	AD1
3rd byte	-	-	-	-	AD2	AD2	AD2
4th byte	-	-	-	-	AD3	AD3	AD3
5th byte	-	-	-	-	-	Dummy	Dummy
Action	sets the (WEL) write enable latch bit	resets the (WEL) write enable latch bit	to read out the values of the status register	to write new values to the status register	n bytes read out until CS# goes high	n bytes read out until CS# goes high	n bytes read out by Dual Output until CS# goes high

Command (byte)	SE (sector erase)	BE (block erase)	CE (chip erase)	PP (page program)	DP (Deep power down)	RDP (Release from deep power down)	RES (read electronic ID)
1st byte	20 (hex)	52 or D8 (hex)	60 or C7 (hex)	02 (hex)	B9 (hex)	AB (hex)	AB (hex)
2nd byte	AD1	AD1	-	AD1	-	-	x
3rd byte	AD2	AD2	-	AD2	-	-	x
4th byte	AD3	AD3	-	AD3	-	-	x
5th byte	-	-	-	-	-	-	-
Action	to erase the selected sector	to erase the selected block	to erase whole chip	to program the selected page	enters deep power down mode	release from deep power down mode	to read out 1-byte Device ID

Command (byte)	RDID (read identification)	REMS (read electronic manufacturer & device ID)	ENSO (enter secured OTP)	EXSO (exit secured OTP)	RDSCUR (read security register)	WRSCUR (write security register)	RDDMC (Read DMC)
1st byte	9F (hex)	90 (hex)	B1 (hex)	C1 (hex)	2B (hex)	2F (hex)	5A (hex)
2nd byte	-	x	-	-	-	-	AD1
3rd byte	-	x	-	-	-	-	AD2
4th byte	-	ADD (Note 1)	-	-	-	-	AD3
5th byte	-	-	-	-	-	-	Dummy
Action	outputs JEDEC ID: 1-byte Manufacturer ID & 2-byte Device ID	output the Manufacturer ID & Device ID	to enter the 512 bit secured OTP mode	to exit the 512 bit secured OTP mode	to read value of security register	to set the lock-down bit as "1" (once lock-down, cannot be updated)	read DMC mode

Note1: ADD=00H will output the manufacturer ID first and ADD=01H will output device ID first.

Note2: It is not recommended to adopt any other code not in the command definition table, which will potentially enter the hidden mode.

10.1. Write Enable (WREN)

The Write Enable (WREN) instruction is for setting Write Enable Latch (WEL) bit. For those instructions like PP, SE, BE, CE, and WRSR, which are intended to change the device content, should be set every time after the WREN instruction setting the WEL bit.

The sequence is shown as Figure 11.

10.2. Write Disable (WRDI)

The Write Disable (WRDI) instruction is for resetting Write Enable Latch (WEL) bit.

The sequence is shown as Figure 12.

The WEL bit is reset by following situations:

- Power-up
- Write Disable (WRDI) instruction completion
- Write Status Register (WRSR) instruction completion
- Page Program (PP) instruction completion
- Sector Erase (SE) instruction completion
- Block Erase (BE) instruction completion
- Chip Erase (CE) instruction completion

10.3. Read Status Register (RDSR)

The RDSR instruction is for reading Status Register Bits. The Read Status Register can be read at any time (even in program/erase/write status register condition) and continuously. It is recommended to check the Write in Progress (WIP) bit before sending a new instruction when a program, erase, or write status register operation is in progress.

The sequence is shown as Figure 13.

The definition of the status register bits is as below:

WIP bit. The Write in Progress (WIP) bit, a volatile bit, indicates whether the device is busy in program/erase/write status register

progress. When WIP bit sets to 1, which means the device is busy in program/erase/write status register progress. When WIP bit sets to 0, which means the device is not in progress of program/erase/write status register cycle.

WEL bit. The Write Enable Latch (WEL) bit, a volatile bit, indicates whether the device is set to internal write enable latch. When WEL bit sets to 1, which means the internal write enable latch is set, the device can accept program/erase/write status register instruction. When WEL bit sets to 0, which means no internal write enable latch; the device will not accept program/erase/write status register instruction. The program/erase command will be ignored and not affect value of WEL bit if it is applied to a protected memory area.

BP2, BP1, BP0 bits. The Block Protect (BP2-BP0) bits, non-volatile bits, indicate the protected area(as defined in table 2) of the device to against the program/erase instruction without hardware protection mode being set. To write the Block Protect (BP2-BP0) bits requires the Write Status Register (WRSR) instruction to be executed. Those bits define the protected area of the memory to against Page Program (PP), Sector Erase (SE), Block Erase (BE) and Chip Erase(CE) instructions (only if all Block Protect bits set to 0, the CE instruction can be executed).

SRWD bit. The Status Register Write Disable (SRWD) bit, non-volatile bit, is operated together with Write Protection (WP#) pin for providing hardware protection mode. The hardware protection mode requires SRWD sets to 1 and WP# pin signal is low stage. In the hardware protection mode, the Write Status Register (WRSR) instruction is no longer accepted for execution and the SRWD bit and Block Protect bits (BP2-BP0) are read only.

Status Register for GPR25L081B

bit7	bit6	bit5	bit4	bit3	bit2	bit1	bit0
SRWD (status register write protect)	0	0	BP2 (level of protected block)	BP1 (level of protected block)	BP0 (level of protected block)	WEL (write enable latch)	WIP (write in progress bit)
1=status register write disable	0	0	(note 1)	(note 1)	(note 1)	1=write enable 0=not write enable	1=write operation 0=not in write operation
Non-volatile bit	0	0	Non-volatile bit	Non-volatile bit	Non-volatile bit	volatile bit	volatile bit

Note1: see the table "Protected Area Size".

10.4. Write Status Register (WRSR)

The WRSR instruction is for changing the values of Status Register Bits. Before sending WRSR instruction, the Write Enable (WREN) instruction must be decoded and executed to set the Write Enable Latch (WEL) bit in advance. The WRSR instruction can change the value of Block Protect (BP2-BP0) bits to define the protected area of memory (as shown in table 1). The WRSR also can set or reset the Status Register Write Disable (SRWD) bit in accordance with Write Protection (WP#) pin signal. The WRSR instruction cannot be executed once the Hardware Protected Mode (HPM) is entered.

The sequence is shown as Figure 14.

The WRSR instruction has no effect on b6, b1, b0 of the status register.

The CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed.

The self-timed Write Status Register cycle time (tW) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be check out during the Write Status Register cycle is in progress. The WIP sets 1 during the tW timing, and sets 0 when Write Status Register Cycle is completed, and the Write Enable Latch (WEL) bit is reset.

Table 5. Protection Modes

Mode	Status register condition	WP# and SRWD bit status	Memory
Software protection mode (SPM)	Status register can be written in (WEL bit is set to "1") and the SRWD, BP2-BP0 bits can be changed	WP#=1 and SRWD bit=0, or WP#=0 and SRWD bit=0, or WP#=1 and SRWD=1	The protected area cannot be program or erase.
Hardware protection mode (HPM)	The SRWD, BP2-BP0 of status register bits cannot be changed	WP#=0, SRWD bit=1	The protected area cannot be program or erase.

Note:

As defined by the values in the Block Protect (BP2-BP0) bits of the Status Register, as shown in Table 1.

As the above table showing, the summary of the Software Protected Mode (SPM) and Hardware Protected Mode (HPM).

Software Protected Mode (SPM):

- When SRWD bit=0, no matter WP# is low or high, the WREN instruction may set the WEL bit and can change the values of SRWD, BP2-BP0. The protected area, which is defined by BP2-BP0 is at software protected mode (SPM).

- When SRWD bit=1 and WP# is high, the WREN instruction may set the WEL bit can change the values of SRWD, BP2-BP0. The protected area, which is defined by BP2-BP0, is at software protected mode (SPM)

Note: If SRWD bit=1 but WP# is low, it is impossible to write the Status Register even if the WEL bit has previously been set. It is rejected to write the Status Register and not be executed.

Hardware Protected Mode (HPM):

- When SRWD bit=1, and then WP# is low (or WP# is low before SRWD bit=1), it enters the hardware protected mode (HPM). The data of the protected area is protected by software protected mode by BP2-BP0 and hardware protected mode by the WP# to against data modification.

Note: to exit the hardware protected mode requires WP# driving high once the hardware protected mode is entered. If the WP# pin is permanently connected to high, the hardware protected mode can never be entered; only can use software protected mode via BP2-BP0.

10.5. Read Data Bytes (READ)

The read instruction is for reading data out. The address is latched on rising edge of SCLK, and data shifts out on the falling edge of SCLK at a maximum frequency fR. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single READ instruction. The address counter rolls over to 0 when the highest address has been reached.

The sequence is shown as Figure 15.

10.6. Read Data Bytes at Higher Speed (FAST_READ)

The FAST_READ instruction is for quickly reading data out. The address is latched on rising edge of SCLK, and data of each bit shifts out on the falling edge of SCLK at a maximum frequency fC. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single FAST_READ instruction. The address counter rolls over to 0 when the highest address has been reached.

The sequence is shown as Figure 16.

While Program/Erase/Write Status Register cycle is in progress, FAST_READ instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.

10.7. Dual Output Mode (DREAD)

The 2READ instruction enable double throughput of Serial Flash in read mode. The address is latched on rising edge of SCLK, and data of every two bits(interleave on 1I/2O pins) shift out on the falling edge of SCLK at a maximum frequency f_T . The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single DREAD instruction. The address counter rolls over to 0 when the highest address has been reached. Once writing DREAD instruction, the following address/dummy/data out will perform as 2-bit instead of previous 1-bit.

The sequence is shown as Figure 17.

While Program/Erase/Write Status Register cycle is in progress, DREAD instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.

The DREAD only perform read operation. Program/Erase /Read ID/Read status/Read ID....operation do not support DREAD throughputs.

10.8. Sector Erase (SE)

The Sector Erase (SE) instruction is for erasing the data of the chosen sector to be "1". The instruction is used for any 4K-byte sector. A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Sector Erase (SE). Any address of the sector (see table 3) is a valid address for Sector Erase (SE) instruction. The CS# must go high exactly at the byte boundary (the latest eighth of address byte been latched-in); otherwise, the instruction will be rejected and not executed.

Address bits [Am-A12] (Am is the most significant address) select the sector address.

The sequence is shown as Figure 18.

The self-timed Sector Erase Cycle time (tSE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be check out during the Sector Erase cycle is in progress. The WIP sets 1 during the tSE timing, and sets 0 when Sector

Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the page is protected by BP2-BP0 bits, the Sector Erase (SE) instruction will not be executed on the page.

10.9. Block Erase (BE)

The Block Erase (BE) instruction is for erasing the data of the chosen block to be "1". The instruction is used for 64K-byte sector erase operation. A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Block Erase (BE). Any address of the block (see table 3) is a valid address for Block Erase (BE) instruction. The CS# must go high exactly at the byte boundary (the latest eighth of address byte been latched-in); otherwise, the instruction will be rejected and not executed.

The sequence is shown as Figure 19.

The self-timed Block Erase Cycle time (tBE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be check out during the Sector Erase cycle is in progress. The WIP sets 1 during the tBE timing, and sets 0 when Sector Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the page is protected by BP2-BP0 bits, the Block Erase (BE) instruction will not be executed on the page.

10.10. Chip Erase (CE)

The Chip Erase (CE) instruction is for erasing the data of the whole chip to be "1". A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Chip Erase (CE). Any address of the sector (see table 3) is a valid address for Chip Erase (CE) instruction. The CS# must go high exactly at the byte boundary(the latest eighth of address byte been latched-in); otherwise, the instruction will be rejected and not executed.

The sequence is shown as Figure 20.

The self-timed Chip Erase Cycle time (tCE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be check out during the Chip Erase cycle is in progress. The WIP sets 1 during the tCE timing, and sets 0 when Chip Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the chip is protected by BP2-BP0 bits, the Chip Erase (CE) instruction will not be executed. It will be only executed when BP2-BP0 all set to "0".

10.11. Page Program (PP)

The Page Program (PP) instruction is for programming the

memory to be "0". A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Page Program (PP). If the eight least significant address bits (A7-A0) are not all 0, all transmitted data which goes beyond the end of the current page are programmed from the start address if the same page (from the address whose 8 least significant address bits (A7-A0) are all 0). The CS# must keep during the whole Page Program cycle. The CS# must go high exactly at the byte boundary (the latest eighth of address byte been latched-in); otherwise, the instruction will be rejected and not executed. If more than 256 bytes are sent to the device, the data of the last 256-byte is programmed at the request page and previous data will be disregarded. If less than 256 bytes are sent to the device, the data is programmed at the request address of the page without effect on other address of the same page.

The sequence is shown as Figure 21.

The self-timed Page Program Cycle time (tPP) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be check out during the Page Program cycle is in progress. The WIP sets 1 during the tPP timing, and sets 0 when Page Program Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the page is protected by BP2-BP0 bits, the Page Program (PP) instruction will not be executed.

10.12. Deep Power-down (DP)

The Deep Power-down (DP) instruction is for setting the device on the minimizing the power consumption (to entering the Deep Power-down mode), the standby current is reduced from ISB1 to ISB2). The Deep Power-down mode requires the Deep Power-down (DP) instruction to enter, during the Deep Power-down mode, the device is not active and all Write/Program/Erase instruction are ignored. When CS# goes high, it's only in standby mode not deep power-down mode. It's different from Standby mode.

The sequence is shown as Figure 22.

Once the DP instruction is set, all instruction will be ignored except the Release from Deep Power-down mode (RDP) and Read Electronic Signature (RES) instruction. (Those instructions allow the ID being reading out). When Powerdown, the deep power-down mode automatically stops, and when power-up, the device automatically is in standby mode. For RDP instruction the CS# must go high exactly at the byte boundary (the latest eighth bit of instruction code been latched-in); otherwise, the instruction will not executed. As soon as Chip Select (CS#) goes high, a

delay of tDP is required before entering the Deep Power-down mode and reducing the current to ISB2).

10.13. Release from Deep Power-down (RDP), Read Electronic Signature (RES)

The Release from Deep Power-down (RDP) instruction is terminated by driving Chip Select (CS#) High. When Chip Select (CS#) is driven High, the device is put in the Stand-by Power mode. If the device was not previously in the Deep Power-down mode, the transition to the Stand-by Power mode is immediate. If the device was previously in the Deep Power-down mode, though, the transition to the Stand-by Power mode is delayed by tRES2, and Chip Select (CS#) must remain High for at least tRES2(max), as specified in Table 6. Once in the Stand-by Power mode, the device waits to be selected, so that it can receive, decode and execute instructions.

RES instruction is for reading out the old style of 8-bit Electronic Signature, whose values are shown as table of ID Definitions. This is not the same as RDID instruction. It is not recommended to use for new design. For new design, please use RDID instruction. Even in Deep power-down mode, the RDP and RES are also allowed to be executed, only except the device is in progress of program/erase/write cycle; there's no effect on the current program/erase/write cycle in progress.

The sequence is shown in Figure 23 and 24.

The RES instruction is ended by CS# goes high after the ID been read out at least once. The ID outputs repeatedly if continuously send the additional clock cycles on SCLK while CS# is at low. If the device was not previously in Deep Power-down mode, the device transition to standby mode is immediate. If the device was previously in Deep Power-down mode, there's a delay of tRES2 to transit to standby mode, and CS# must remain to high at least tRES2(max). Once in the standby mode, the device waits to be selected, so it can be receive, decode, and execute instruction.

The RDP instruction is for releasing from Deep Power Down Mode.

10.14. Read Identification (RDID)

The RDID instruction is for reading the manufacturer ID of 1-byte and followed by Device ID of 2-byte. The Manufacturer ID and Device ID are listed as table of "ID Definitions".

The sequence is shown as Figure 25.

While Program/Erase operation is in progress, it will not decode the RDID instruction, so there's no effect on the cycle of program/erase operation which is currently in progress. When CS# goes high, the device is at standby stage.

10.15. Read Electronic Manufacturer ID & Device ID (REMS)

The REMS instruction is an alternative to the Release from Power-down/Device ID instruction that provides both the JEDEC assigned manufacturer ID and the specific device ID.

The REMS instruction is very similar to the Release from

Power-down/Device ID instruction. The instruction is initiated by driving the CS# pin low and shift the instruction code "90h" or "EFh" followed by two dummy bytes and one bytes address (A7~A0). After which, the Manufacturer ID and the Device ID are shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in figure 26. The Device ID values are listed in Table of ID Definitions. If the one-byte address is initially set to 01h, then the device ID will be read first and then followed by the Manufacturer ID. The Manufacturer and Device IDs can be read continuously, alternating from one to the other. The instruction is completed by driving CS# high.

Table6. ID Definitions

Command Type	GPR25L081B		
	RDID Command	manufacturer ID C2	memory type 20
RES Command	electronic ID 13		
REMS	manufacturer ID C2	device ID 13	

10.16. Enter Secured OTP (ENSO)

The ENSO instruction is for entering the additional 512 bit secured OTP mode. The additional 512 bit secured OTP is independent from main array, which may use to store unique serial number for system identifier. After entering the Secured OTP mode, and then follow standard read or program, procedure to read out the data or update data. The Secured OTP data cannot be updated again once it is lock-down.

Please note that WRSR/WRSCUR commands are not acceptable during the access of secure OTP region, once security OTP is lock down, only read related commands are valid.

10.17. Exit Secured OTP (EXSO)

The EXSO instruction is for exiting the additional 512 bit secured OTP mode.

10.18. Read Security Register (RDSCUR)

The RDSCUR instruction is for reading the value of Security Register bits. The Read Security Register can be read at any time (even in program/erase/write status register/write security register condition) and continuously.

The definition of the Security Register bits is as below:

Secured OTP Indicator bit. The Secured OTP indicator bit shows the chip is locked by factory before ex- factory or not. When it is "0", it indicates non- factory lock; "1" indicates factory- lock.

Lock-down Secured OTP (LDSO) bit. By writing WRSCUR instruction, the LDSO bit may be set to "1" for customer lock-down purpose. However, once the bit is set to "1" (lock-down), the LDSO bit and the 512 bit Secured OTP area cannot be update any more. While it is in 512 bit secured OTP mode, array access is not allowed.

Table7. Security Register Definition

bit7	bit6	bit5	bit4	bit3	bit2	bit1	bit0
x	x	x	x	x	x	LDSO (indicate if lock-down)	Secured OTP indicator bit
reserved	reserved	reserved	reserved	reserved	reserved	0 = not lockdown 1 = lock-down (cannot program/erase OTP)	0 = nonfactory lock 1 = factory lock
volatile bit	volatile bit	volatile bit	volatile bit	volatile bit	volatile bit	non-volatile bit	non-volatile bit

10.19. Write Security Register (WRSCUR)

The WRSCUR instruction is for changing the values of Security Register Bits. Unlike write status register, the WREN instruction is not required before sending WRSCUR instruction. The WRSCUR instruction may change the values of bit1 (LDSO bit) for customer to lock-down the 512 bit Secured OTP area. Once the LDSO bit is set to "1", the Secured OTP area cannot be updated any more.

The CS# must go high exactly at the boundary; otherwise, the instruction will be rejected and not executed.

10.20. Read DMC mode (RDDMC)

GPR25L081B features DMC mode. Host system can retrieve the

operating characteristics, structure and vendor-specified information such as identifying information, memory size, operating voltages and timing information of this device by DMC mode. Writes the DMC Query command "5AH". The system can read DMC information at the addresses given. A reset command is required to exit DMC mode and go back to ready array mode. The system can write the DMC Query command only when the device is in read mode. The DMC information at the address given in DMC code table.

The identification data values in under TBD status. The sequence of issuing RDDMC instruction is CS# goes low→send RDDMC (5A) instruction→send 3 address bytes on SI pin→send 1 dummy byte on SI pin→read DMC code→CS# goes high.

Discoverable Memory Capabilities (DMC) Signature and Parameter Identification Data Values

Description		Address (h) (Byte Mode)	Address (Bit)	Data	Comment
SPI Flash Discoverability Parameters (SFDP) Signature		00h	7:0	53h	Hex: 50444653
		01h	15:8	46h	
		02h	23:16	44h	
		03h	31:24	50h	
SFDP Revision	Minor Revision	04h	7:0	00h	Start from 0x00
	Major Revision	05h	15:8	01h	Start from 0x01
Number of Parameter Header		06h	23:16	02h	
Reserved		07h	31:24	Reserved	
Parameter ID(0)		08h	7:0	00h	
Parameter Minor Revision		09h	15:8	00h	Start from 0x00
Parameter Major Revision		0Ah	23:16	01h	Start from 0x01
Parameter Length (in DW)		0Bh	31:24	02h	Based on Intel draft
Parameter Table Pointer		0Eh:0Ch	23:00	000020h	
Reserved		0Fh	31:24	Reserved	
Parameter ID(1)		10h	7:0	01h	
Parameter Minor Revision		11h	15:8	00h	Start from 0x00
Parameter Major Revision		12h	23:16	01h	Start from 0x01
Parameter Length (in DW)		13h	31:24	Reserved	Reserved
Parameter Table Pointer		16h:14h	23:00	Reserved	Address reserved
Reserved		17h	31:24	Reserved	
Parameter ID(2)		18h	7:0	02h	
Parameter Minor Revision		19h	15:8	00h	Start from 0x00
Parameter Major Revision		1Ah	23:16	01h	Start from 0x01
Parameter Length (in DW)		1Bh	31:24	02h	
Parameter Table Pointer		1Eh:1Ch	23:00	000030h	
Reserved		1Fh	31:24	Reserved	

Parameter ID (0)

Description	Address (h) (Byte Mode)	Address (Bit)	Data	Comment
Minimum Block/Sector Erase sizes	20h	01:00	01	00=reserved 01=4KB erase 10=reserved 11=64KB erase
Write Granularity		02	1	0= 1Byte 1=64Byte
Write Enable Command Required for Writing to Volatile Status Registers		04:03	00	00=N/A 01=use 50h opcode 11=use 06h opcode
Reserved		07:05	Reserved	Reserved
4KB Erase Opcode	21h	15:08	20h	4KB Erase Support (00h=not supported)
Supports Single Input Address Dual Output Fast read	22h	16	1	0=not supported 1=support
Number of bytes used in addressing for flash array read, write and erase		18:17	00	00=3Byte 01=4Byte 10=reserved 11=reserved
Supports Dual Transfer Rate Clocking		19	0	0=not supported 1=support
Supports Dual Input Address Dual Output Fast read		20	0	0=not supported 1=support
Supports Quad Input Address Quad Output Fast read		21	0	0=not supported 1=support
Reserved		23:22	Reserved	Reserved
		23h	31:24	
Flash Size in bits	24h to 27h	31:00	007FFFFh	8Mb

Parameter ID (1)

Description	Address (h) (Byte Mode)	Address (Bit)	Data	Comment
Reserved	Undefined	31:00	Reserved	Reserved

Parameter ID (2)

Description	Address (h) (Byte Mode)	Address (Bit)	Data	Comment
V _{CC} Supply Maximum Voltage	31h:30h	15:00	3600h	200h=2.00V 280h=2.80V 360h=3.60V
V _{CC} Supply Minimum Voltage	33h:32h	23:15	2700h	165h=1.65V 225h=2.25V 235h=2.35V 270h=2.70V

Description	Address (h) (Byte Mode)	Address (Bit)	Data	Comment
V _{PP} Supply Maximum Voltage	34h	01:00	00	00=not supported
V _{PP} Supply Minimum Voltage		03:02	00	00=not supported
Supports V _{IO} Function		04	0	0=not supported 1=support
Supports HOLD# Function		05	1	0=not supported 1=support
Reserved		07:06	Reserved	reserved
Parallel Mode Capable	35h	08	0	0=not supported 1=support
Supports Single Input Address Quad Output Fast read		09	0	0=not supported 1=support
Supports Continuous Program Mode		10	0	0=not supported 1=support
Supports Deep Power Down Mode		11	1	0=not supported 1=support
OTP Capable		12	1	0=not supported 1=support
Supports Sector Group Protect		13	1	0=not supported 1=support
Supports independent Block Protect		14	0	0=not supported 1=support
Supports boot Sector Protect		15	0	0=not supported 1=support
Supports 64KB Block Erase		36h	16	1
Supports 32KB Block Erase	17		0	0=not supported 1=support
Reserved	23:18		Reserved	Reserved
	37h	31:24		

11. POWER-ON STATE

The device is at below states when power-up:

- Standby mode (please note it is not deep power-down mode)
- Write Enable Latch (WEL) bit is reset

The device must not be selected during power-up and power-down stage unless the VCC achieves below correct level:

- VCC minimum at power-up stage and then after a delay of tVSL
- GND at power-down

Please note that a pull-up resistor on CS# may ensure a safe and proper power-up/down level.

An internal power-on reset (POR) circuit may protect the device from data corruption and inadvertent data change during power up state.

For further protection on the device, if the VCC does not reach the

VCC minimum level, the correct operation is not guaranteed.

The read, write, erase, and program command should be sent after the below time delay:

- tVSL after VCC reached VCC minimum level

The device can accept read command after VCC reached VCC minimum and a time delay of tVSL.

Please refer to the figure of "power-up timing".

Note:

- To stabilize the VCC level, the VCC rail decoupled by a suitable capacitor close to package pins is recommended.(generally around 0.1uF)

11.1. Initial Delivery State

The device is delivered with the memory array erased: all bits are set to 1 (each byte contains FFh). The Status Register contains 00h (all Status Register bits are 0).

12. ELECTRICAL SPECIFICATIONS

12.1. Absolute Maximum Ratings

Rating		Value
Ambient Operating Temperature	Industrial grade	-40°C to 85°C
Storage Temperature		-55°C to 125°C
Applied Input Voltage		-0.5V to 4.6V
Applied Output Voltage		-0.5V to 4.6V
VCC to Ground Potential		-0.5V to 4.6V

Notice:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is stress rating only and functional operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended period may affect reliability.
2. Specifications contained within the following tables are subject to change.
3. During voltage transitions, all pins may overshoot V_{SS} to $-2.0V$ and V_{CC} to $+2.0V$ for periods up to 20ns, see Figure 3 and 4.

Figure 3. Maximum Negative Overshoot Waveform

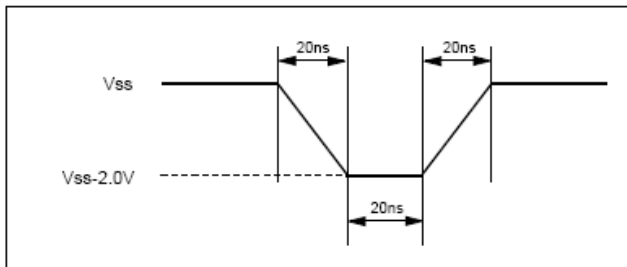
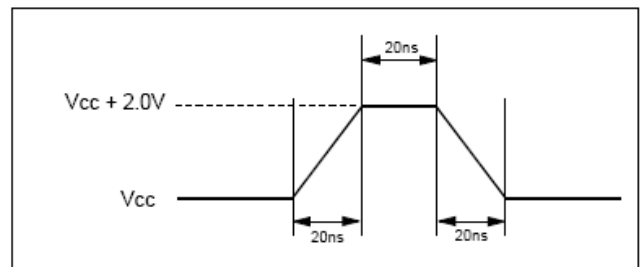


Figure 4. Maximum Positive Overshoot Waveform



12.2. Capacitance TA = 25°C, f = 1.0 MHz

Symbol	Parameter	Min.	Typ.	Max.	Unit	Conditions
CIN	Input Capacitance	-	-	6	pF	VIN = 0V
COUT	Output Capacitance	-	-	8	pF	VOUT = 0V

Figure 5. Input Test Waveforms and Measurement Level

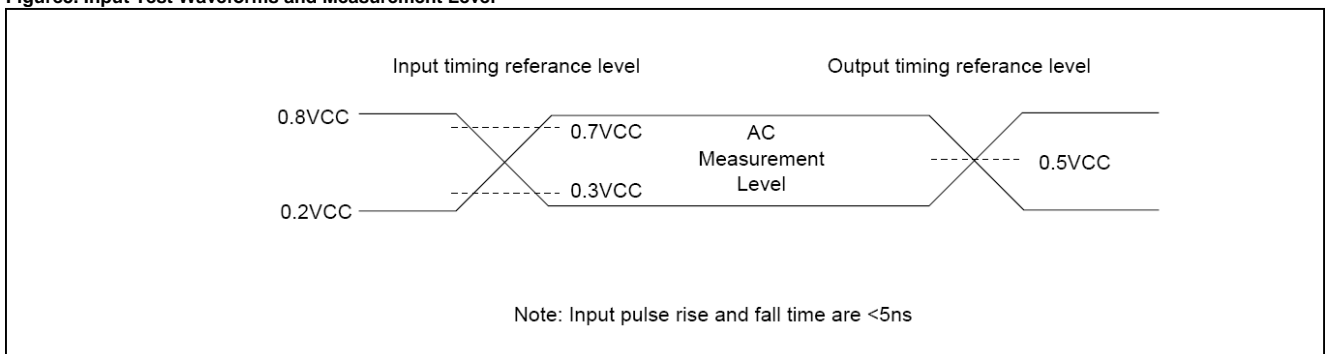
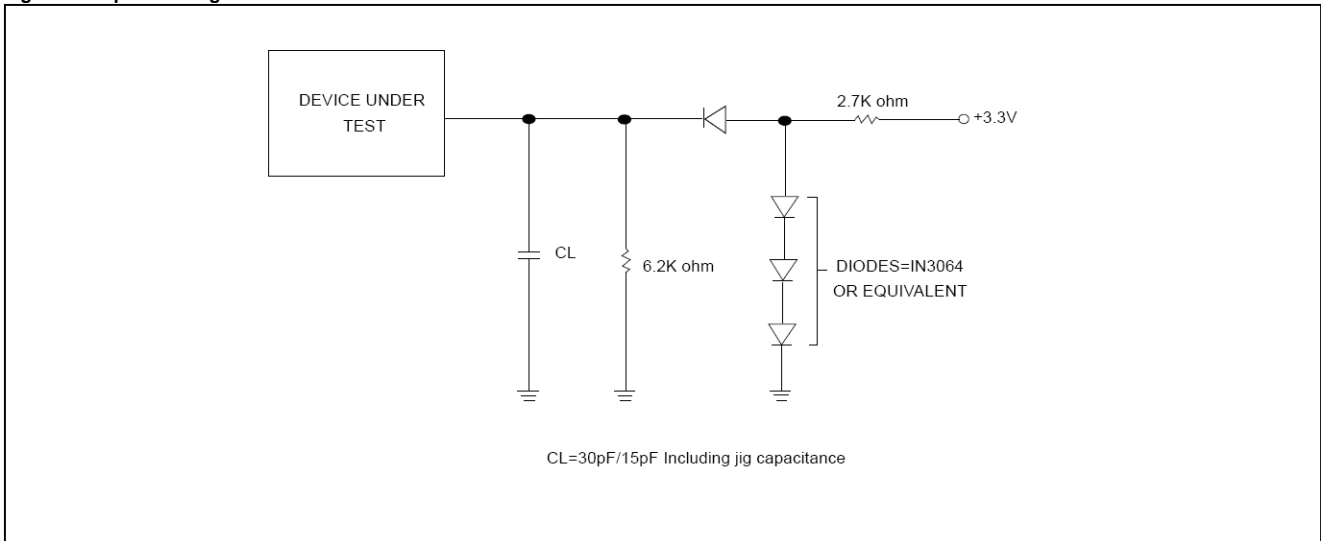


Figure6. Output Loading



12.3. DC Characteristics

Symbol	Parameter	Notes	Min.	Typ.	Max.	Units	Test Conditions
ILI	Input Load Current	1	-	-	± 2	uA	VCC = VCC Max, VIN = VCC or GND
ILO	Output Leakage Current	1	-	-	± 2	uA	VCC = VCC Max, VIN = VCC or GND
ISB1	VCC Standby Current	1	-	-	50	uA	VIN = VCC or GND, CS# = VCC
ISB2	Deep Power-down Current		-	5	10	uA	VIN = VCC or GND, CS# = VCC
ICC1	VCC Read	1	-	-	12	mA	f=86MHz fT=80MHz (2 x I/O read) SCLK=0.1VCC/0.9VCC, SO=Open
		1	-	-	12	mA	f=66MHz, SCLK=0.1VCC/0.9VCC, SO=Open
		1	-	-	4	mA	f=33MHz, SCLK=0.1VCC/0.9VCC, SO=Open
ICC2	VCC Program Current (PP)	1	-	-	20	mA	Program in Progress, CS# = VCC
ICC3	VCC Write Status Register (WRSR) Current	1	-	-	15	mA	Program status register in progress, CS#=VCC
ICC4	VCC Sector Erase Current (SE)	1	-	-	15	mA	Erase in Progress, CS#=VCC
ICC5	VCC Chip Erase Current (CE)	1	-	-	20	mA	Erase in Progress, CS#=VCC
VIL	Input Low Voltage		-0.5	-	0.3VCC	V	
VIH	Input High Voltage		0.7VCC	-	VCC+0.4	V	
VOL	Output Low Voltage		-	-	0.4	V	IOL = 1.6mA
VOH	Output High Voltage		VCC-0.2	-	-	V	IOH = -100uA

Notes:

1. Typical values at VCC = 3.3V, T = 25°C. These currents are valid for all product versions (package and speeds).
2. Not 100% tested.

12.4. AC Characteristics

Symbol	Alt.	Parameter	Min.	Typ.	Max.	Unit	
fSCLK	fC	Clock Frequency for the following instructions: FAST_READ, PP, SE, BE, CE, DP, RES, RDP, WREN, WRDI, RDID, RDSR, WRSR	10KHz	-	86	MHz	
fRSCLK	fR	Clock Frequency for READ instructions	10KHz	-	33	MHz	
fTSCLK	fT	Clock Frequency for 2READ instructions	10KHz	-	80	MHz	
tCH(1)	tCLH	Clock High Time	fC=86MHz	5.5	-	-	ns
			fR=33MHz	13	-	-	ns
tCL(1)	tCLL	Clock Low Time	fC=86MHz	5.5	-	-	ns
			fR=33MHz	13	-	-	ns
tCLCH(2)		Clock Rise Time (3) (peak to peak)	0.1	-	-	V/ns	
tCHCL(2)		Clock Fall Time (3) (peak to peak)	0.1	-	-	V/ns	
tSLCH	tCSS	CS# Active Setup Time (relative to SCLK)	5	-	-	ns	
tCHSL		CS# Not Active Hold Time (relative to SCLK)	5	-	-	ns	
tDVCH	tDSU	Data In Setup Time	2	-	-	ns	
tCHDX	tDH	Data In Hold Time	5	-	-	ns	
tCHSH		CS# Active Hold Time (relative to SCLK)	5	-	-	ns	
tSHCH		CS# Not Active Setup Time (relative to SCLK)	5	-	-	ns	
tSHSL	tCSH	CS# Deselect Time	Read	15	-	-	ns
			Write	40	-	-	ns
tSHQZ(2)	tDIS	Output Disable Time	-	-	6	ns	
tCLQV	tV	Clock Low to Output Valid, Loading 30pF/15pF	-	-	8/6	ns	
tCLQX	tHO	Output Hold Time	0	-	-	ns	
tHLCH		HOLD# Setup Time (relative to SCLK)	5	-	-	ns	
tCHHH		HOLD# Hold Time (relative to SCLK)	5	-	-	ns	
tHHCH		HOLD Setup Time (relative to SCLK)	5	-	-	ns	
tCHHL		HOLD Hold Time (relative to SCLK)	5	-	-	ns	
tHHQX(2)	tLZ	HOLD to Output Low-Z	-	-	6	ns	
tHLQZ(2)	tHZ	HOLD# to Output High-Z	-	-	6	ns	
tWHSL(4)		Write Protect Setup Time	20	-	-	ns	
tSHWL(4)		Write Protect Hold Time	100	-	-	ns	
tDP(2)		CS# High to Deep Power-down Mode	-	-	10	us	
tRES1(2)		CS# High to Standby Mode without Electronic Signature Read	-	-	8.8	us	
tRES2(2)		CS# High to Standby Mode with Electronic Signature Read	-	-	8.8	us	
tW		Write Status Register Cycle Time	-	40	100	ms	
tBP		Byte-Program	-	9	300	us	
tPP		Page Program Cycle Time	-	1.4	5	ms	
tSE		Sector Erase Cycle Time	-	60	300	ms	
tBE		Block Erase Cycle Time	-	0.7	2	s	
tCE		Chip Erase Cycle Time	-	7	15	s	

Notes:

1. tCH + tCL must be greater than or equal to 1/ fC. For Fast Read, tCL/tCH=5.5/5.5.
2. Value guaranteed by characterization, not 100% tested in production.
3. Expressed as a slew-rate.
4. Only applicable as a constraint for a WRSR instruction when SRWD is set at 1.
5. Test condition is shown as Figure 5.

12.5. Timing Analysis

Figure7. Serial Input Timing

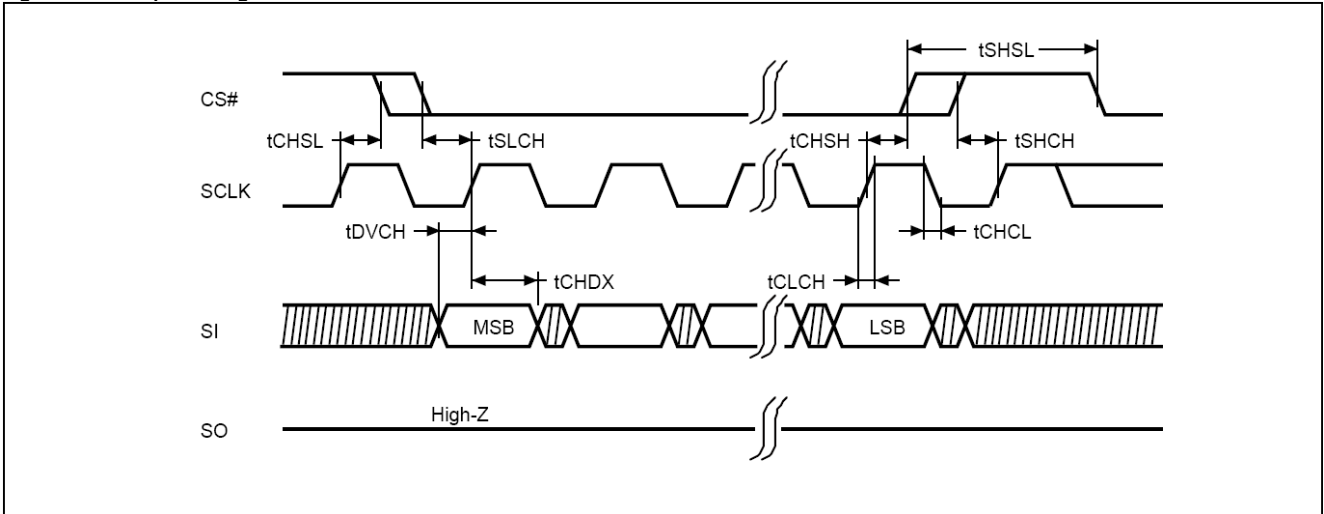


Figure8. Output Timing

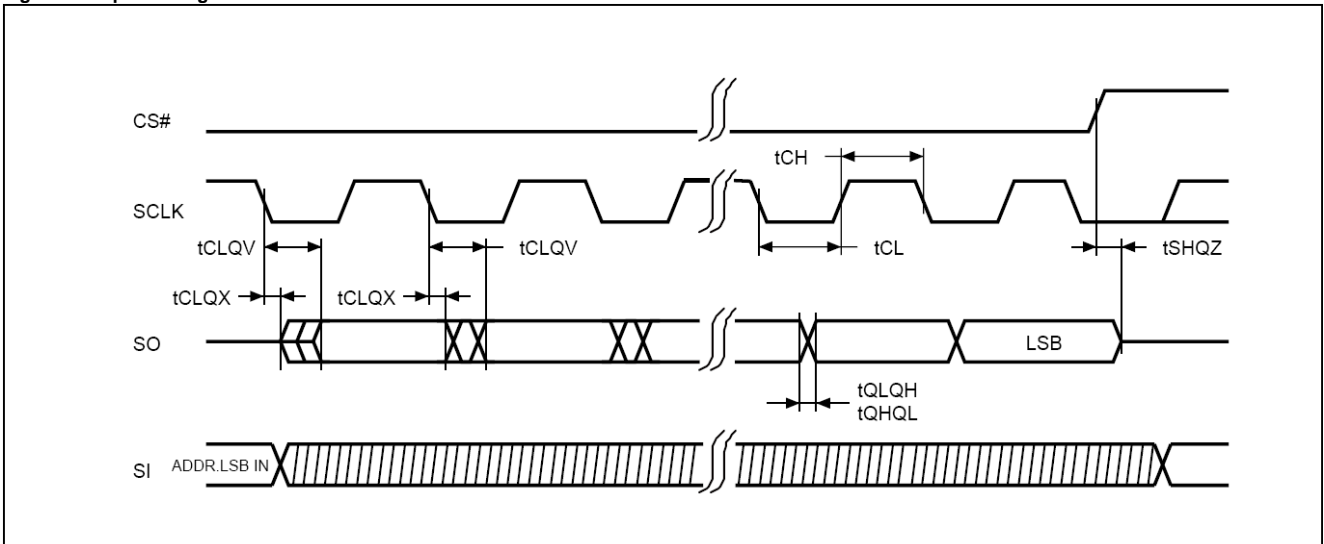
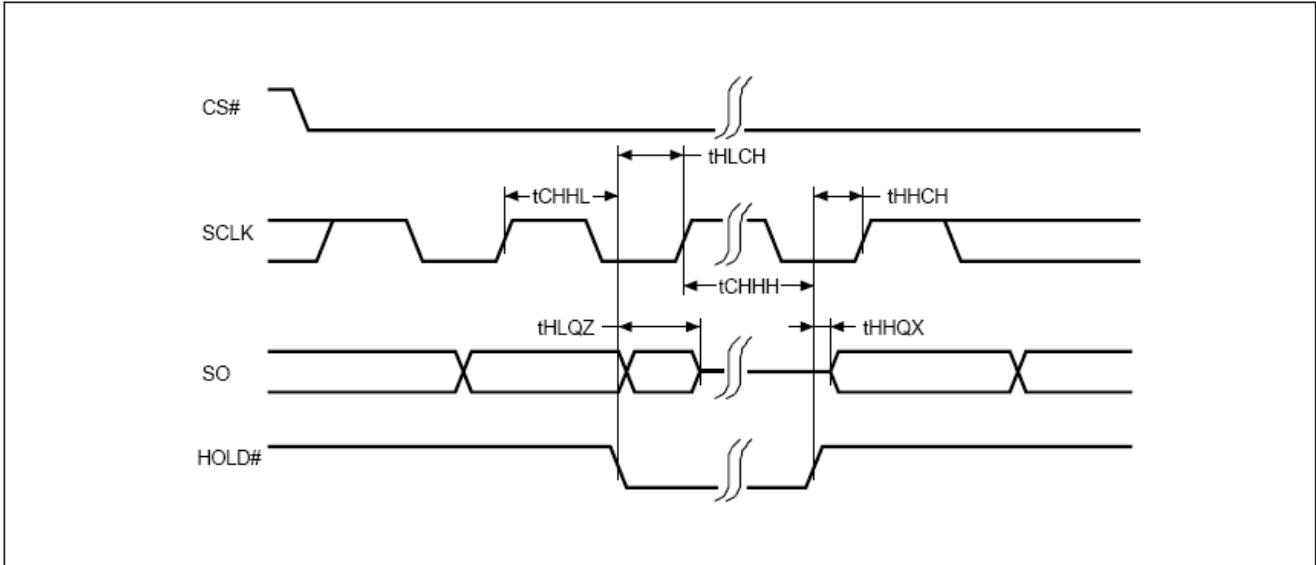


Figure9. Hold Timing



* SI is "don't care" during HOLD operation.

Figure10. WP# Disable Setup and Hold Timing during WRSR when SRWD=1

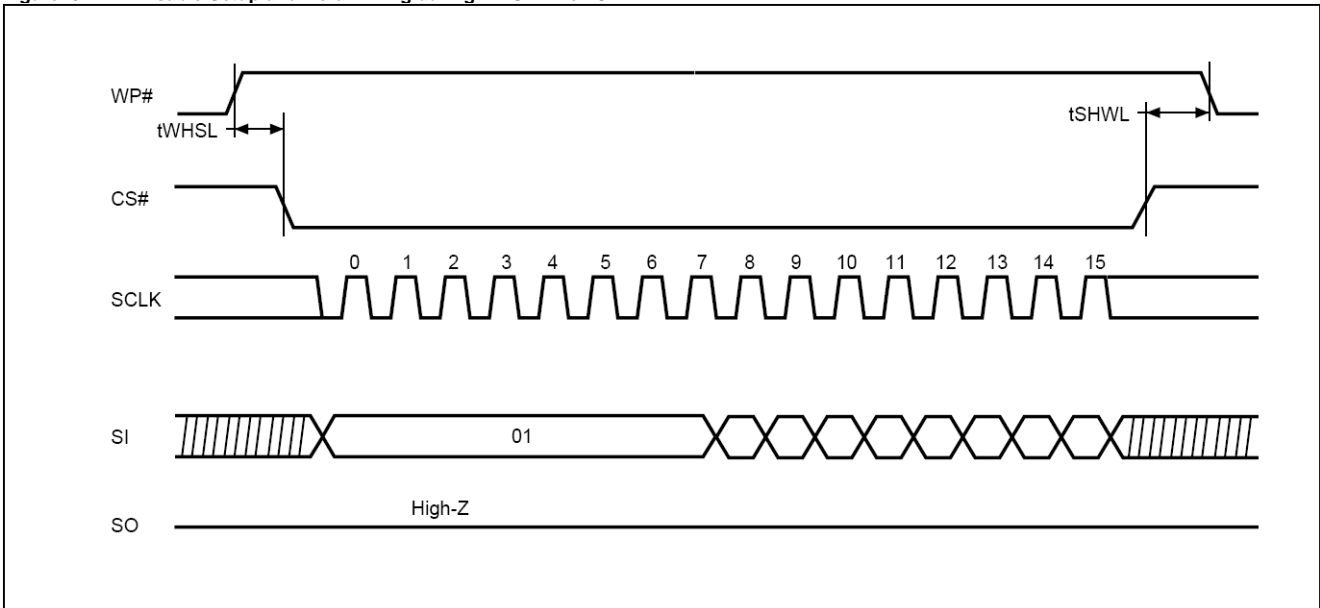


Figure11. Write Enable (WREN) Sequence (Command 06)

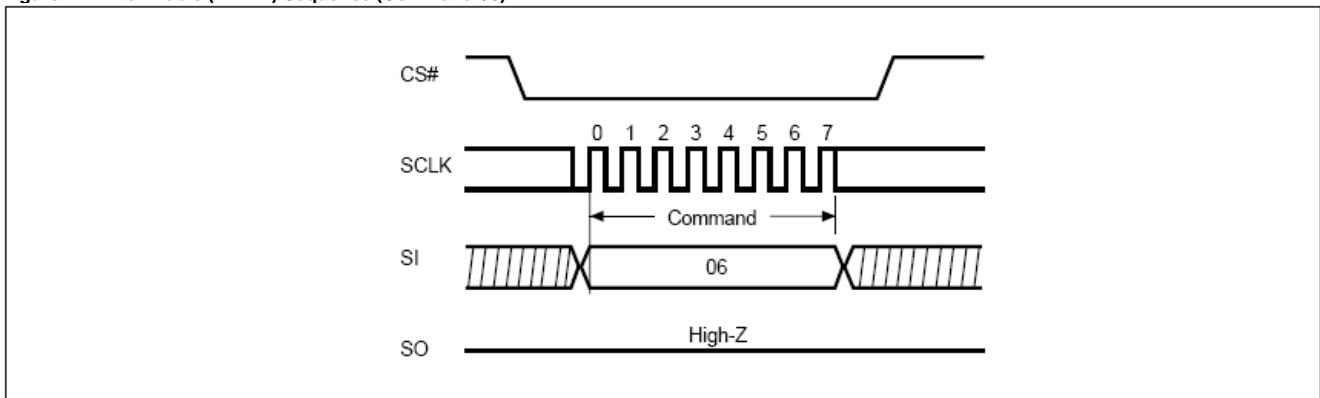


Figure12. Write Disable (WRDI) Sequence (Command 04)

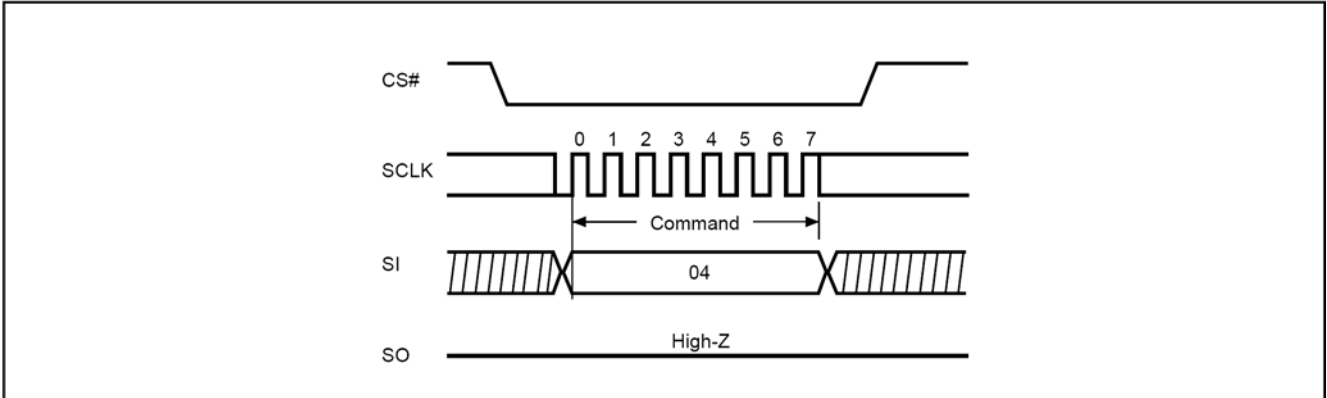


Figure13. Read Status Register (RDSR) Sequence (Command 05)

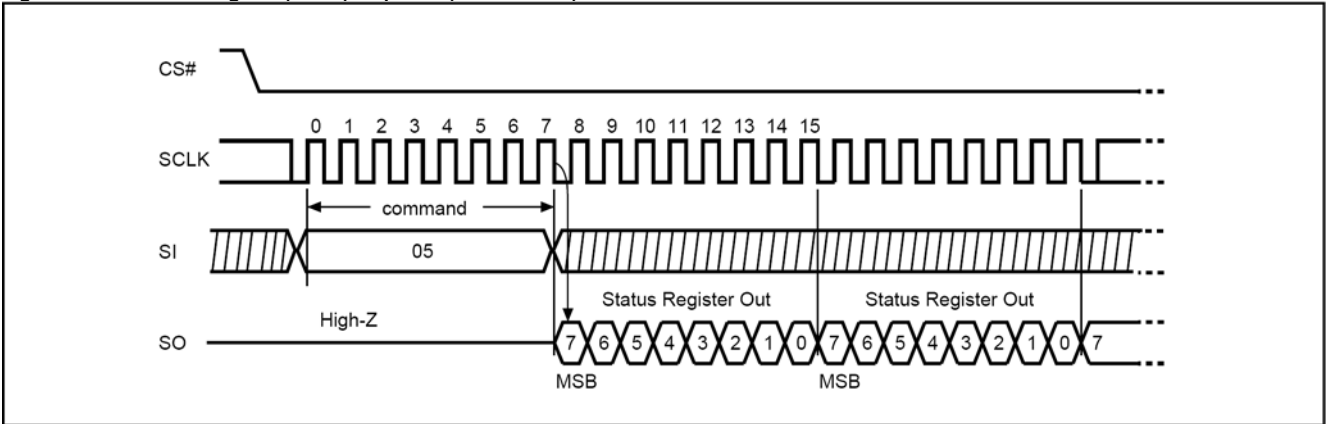


Figure14. Write Status Register (WRSR) Sequence (Command 01)

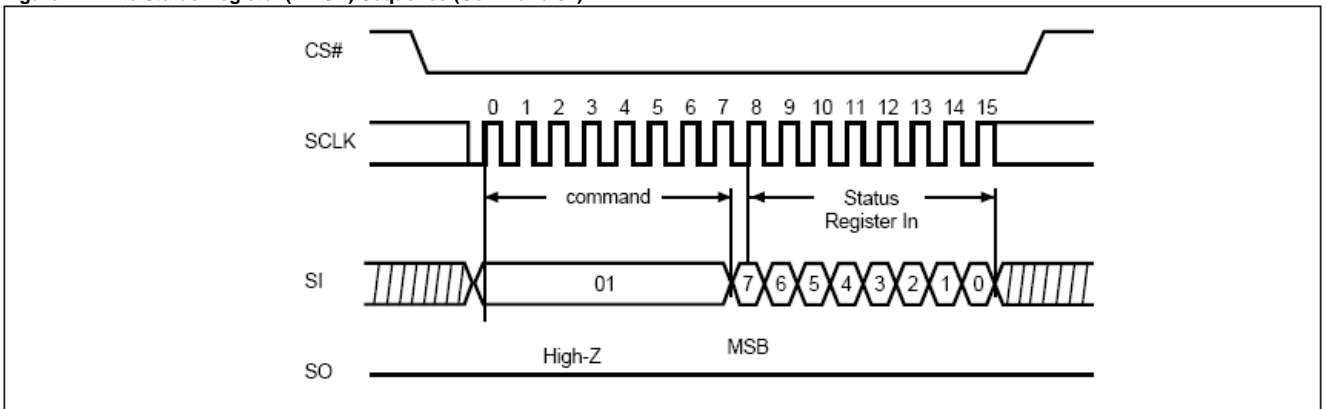


Figure15. Read Data Bytes (READ) Sequence (Command 03)

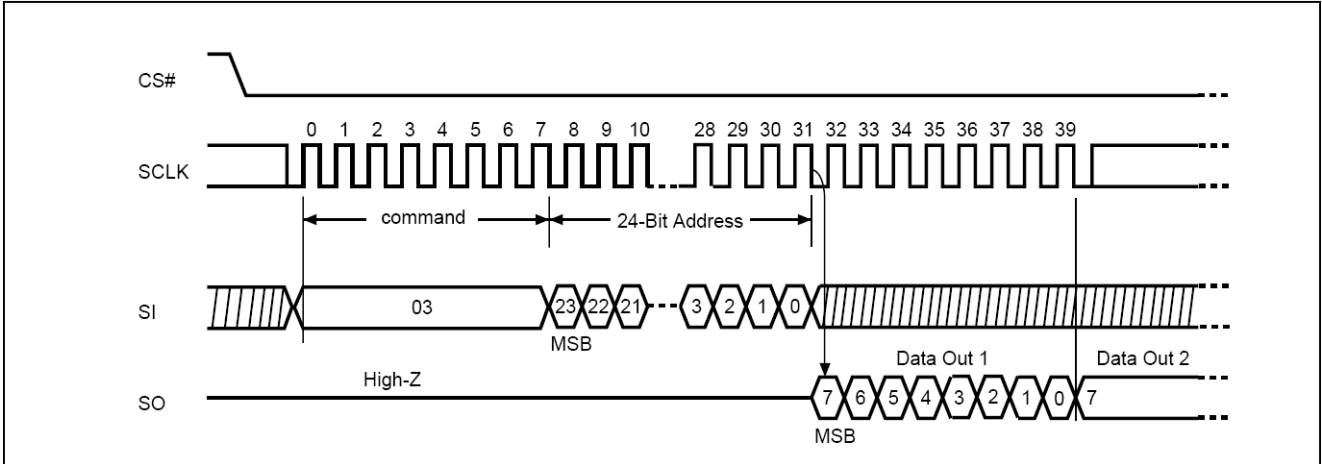


Figure16. Read at Higher Speed (FAST_READ) Sequence (Command 0B)

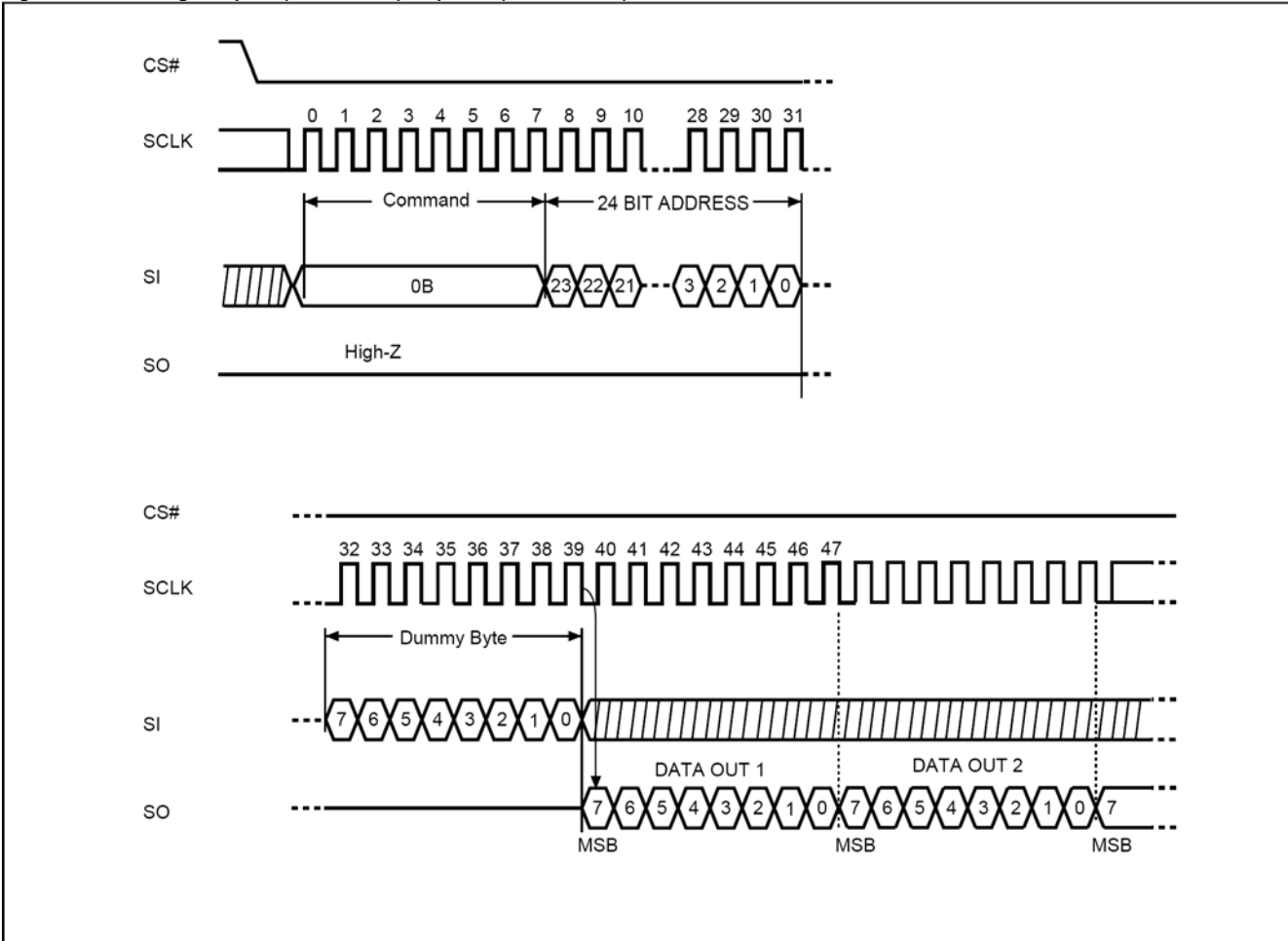


Figure17. Dual Output Read Mode Sequence (Command 3B)

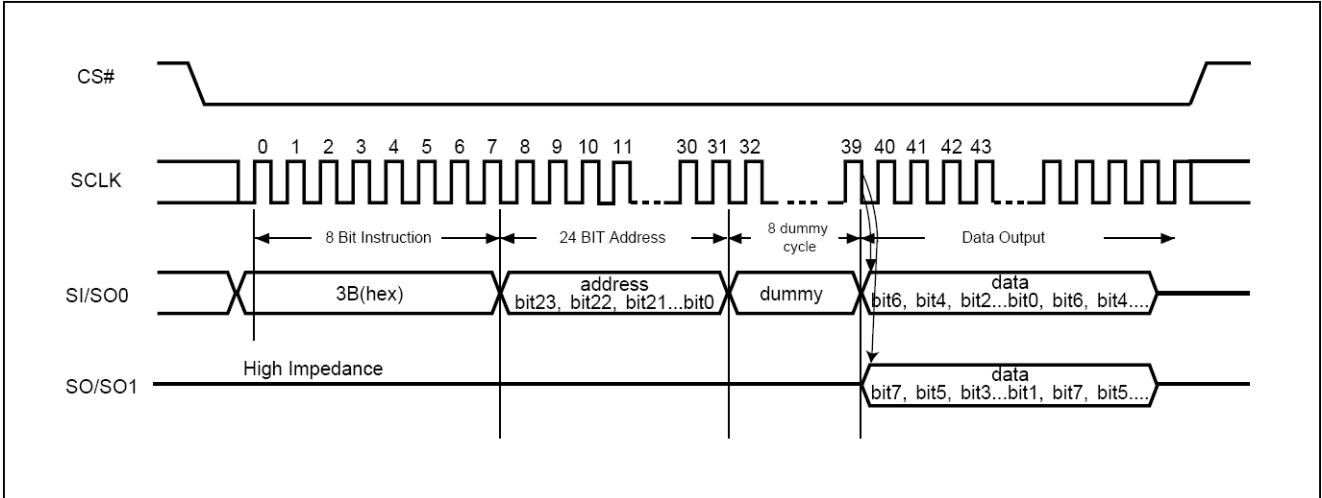
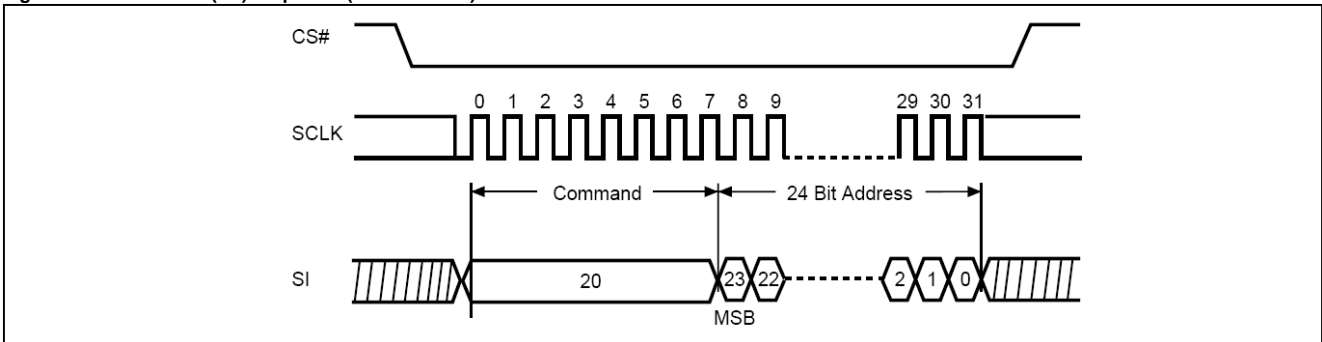
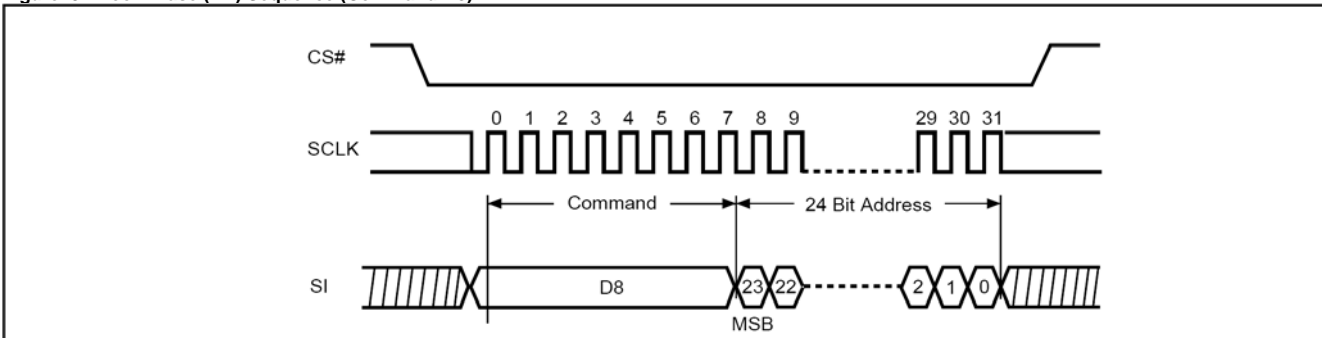


Figure18. Sector Erase (SE) Sequence (Command 20)



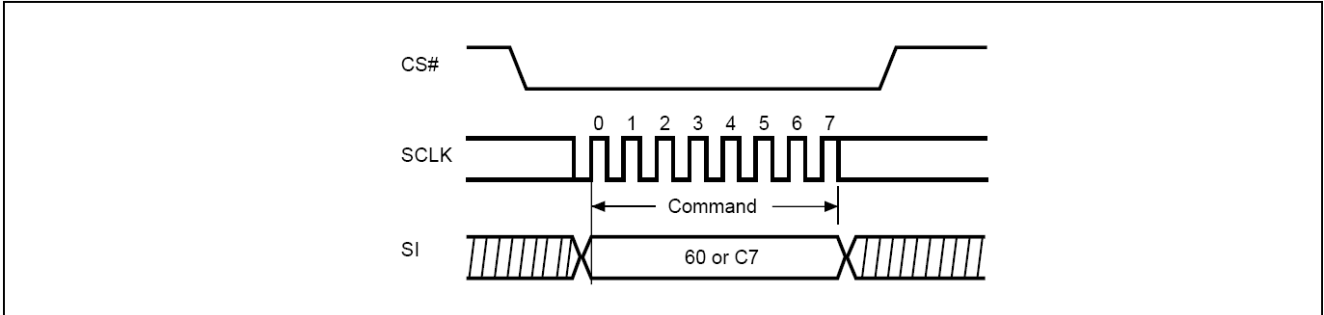
Note: SE command is 20(hex).

Figure19. Block Erase (BE) Sequence (Command D8)



Note: BE command is D8(hex).

Figure20. Chip Erase (CE) Sequence (Command 60 or C7)



Note: CE command is 60(hex) or C7(hex).

Figure21. Page Program (PP) Sequence (Command 02)

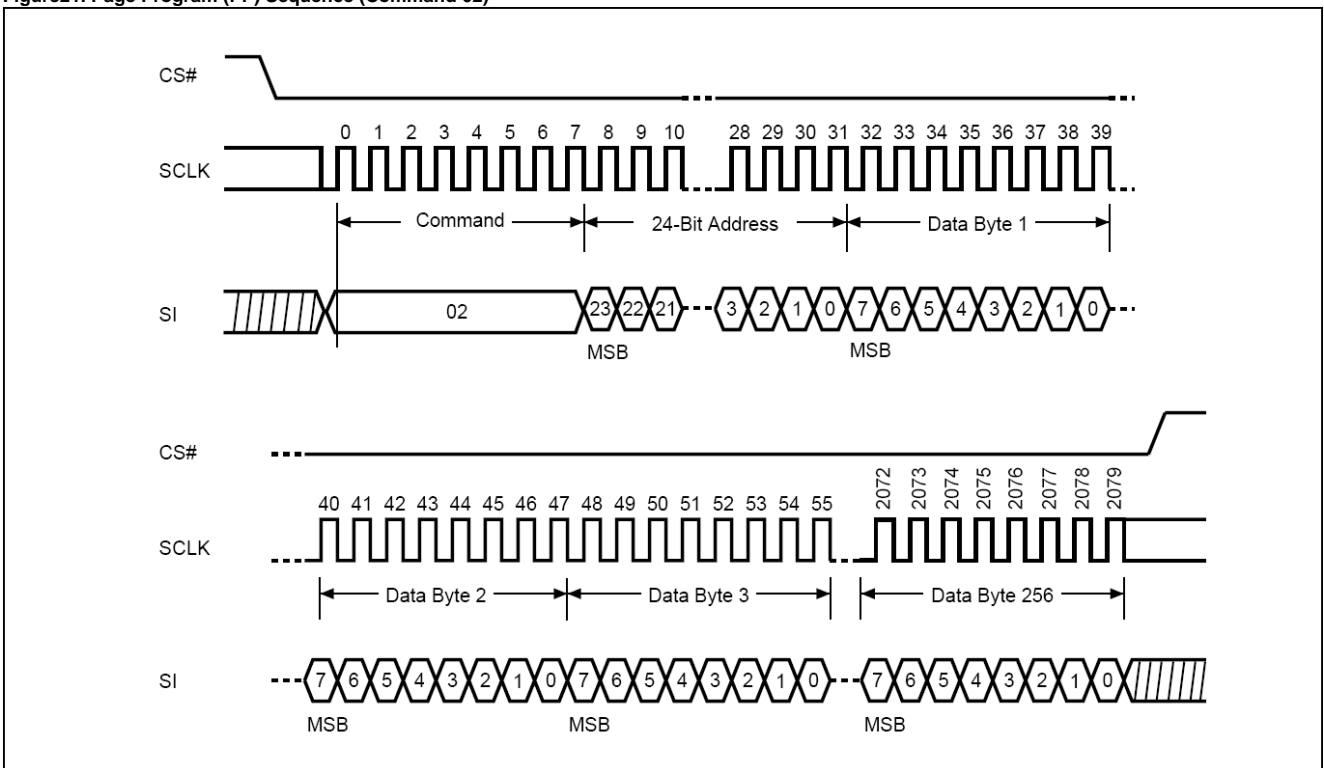


Figure22. Deep Power-down (DP) Sequence (Command B9)

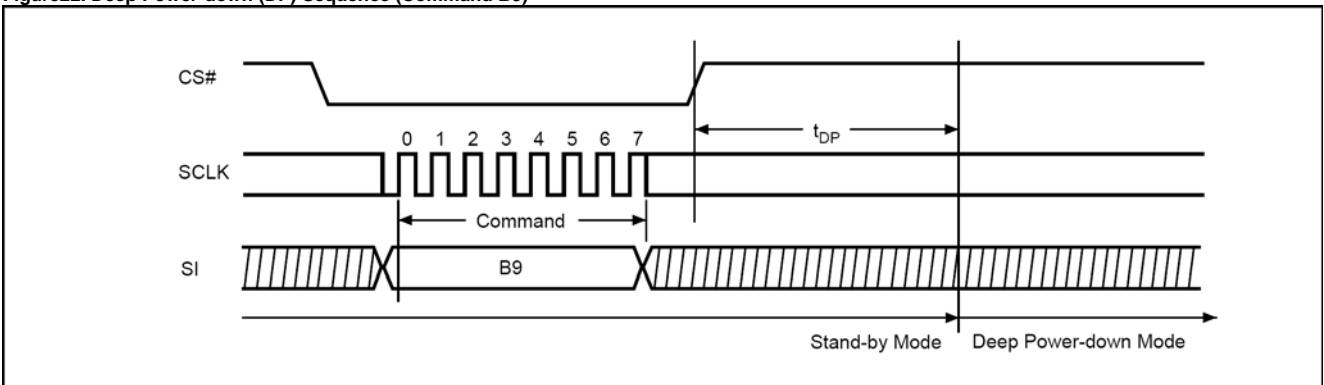


Figure23. Release from Deep Power-down (RDP) Sequence (Command AB)

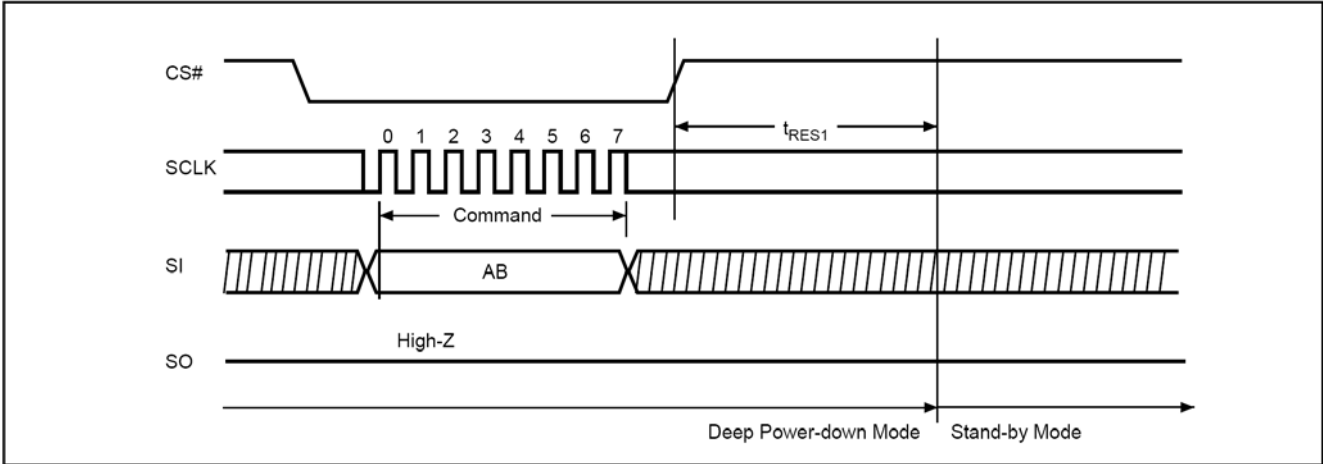


Figure24. Release from Deep Power-down and Read Electronic Signature (RES) Sequence (Command AB)

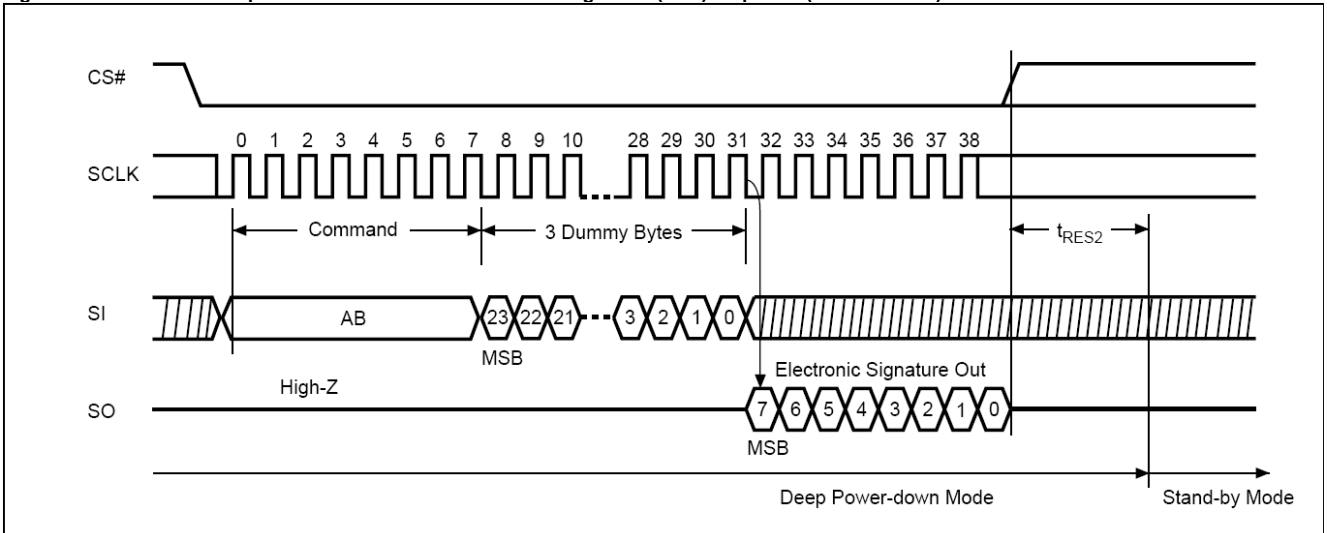


Figure25. Read Identification (RDID) Sequence (Command 9F)

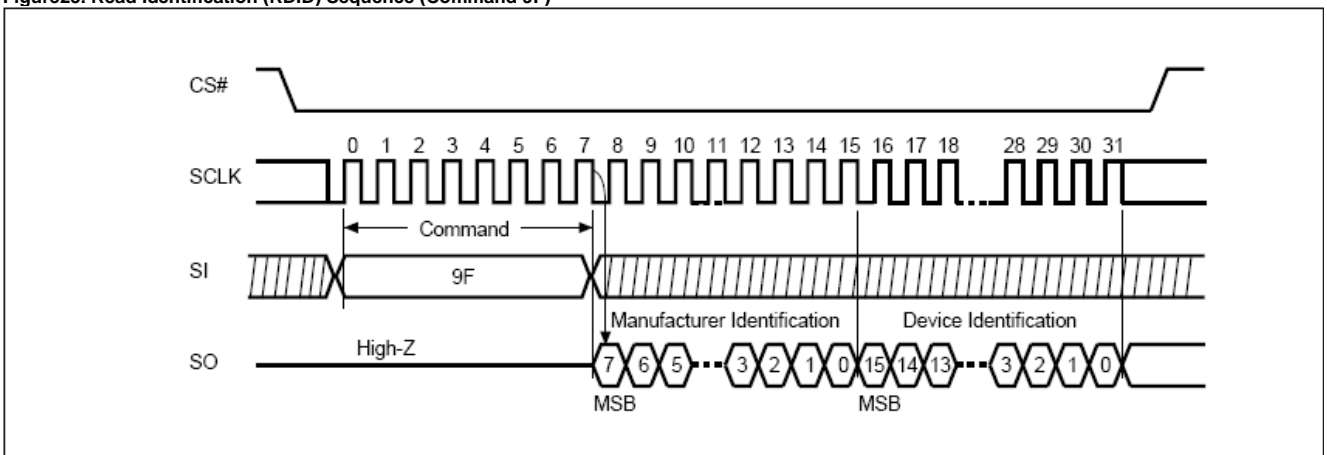
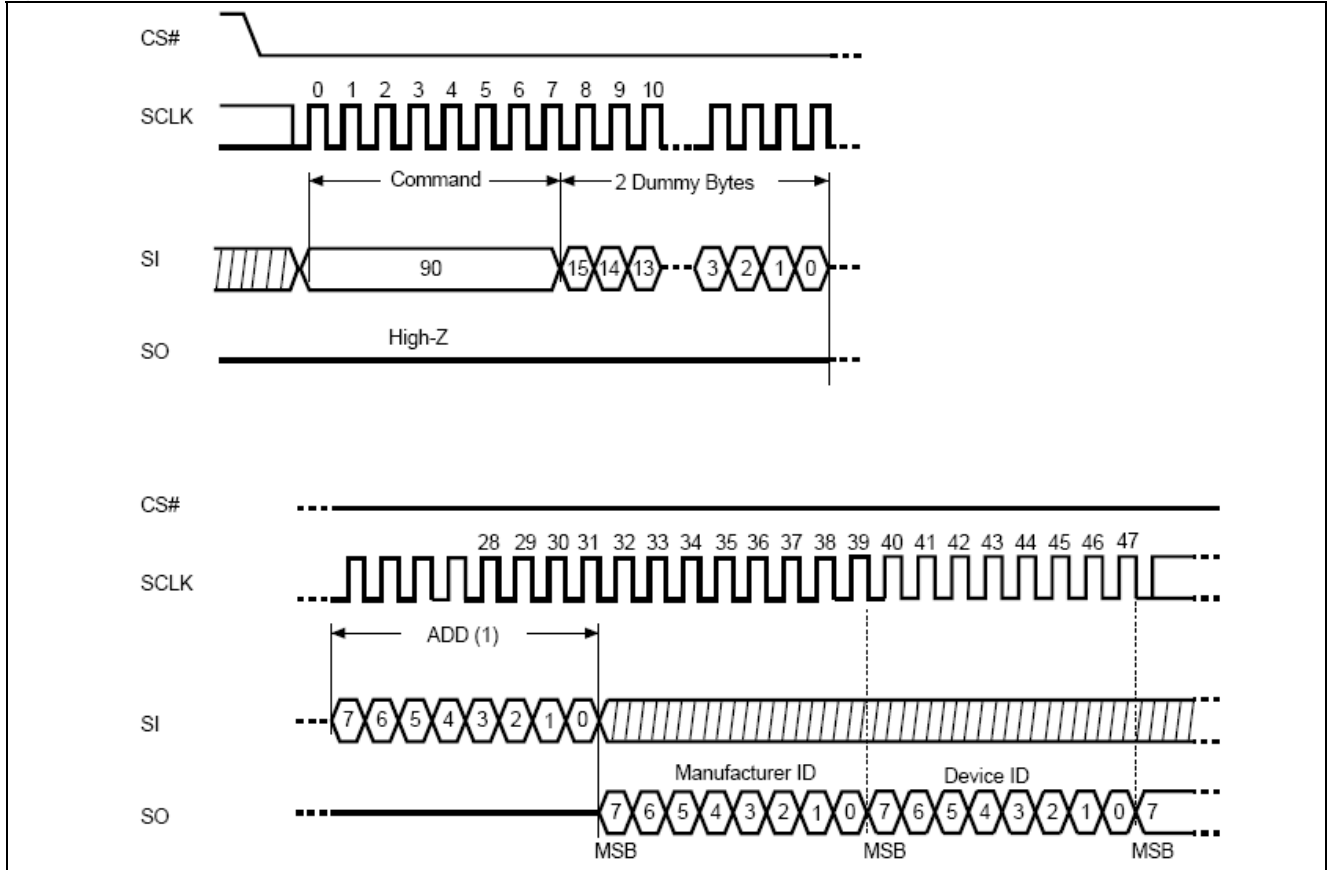


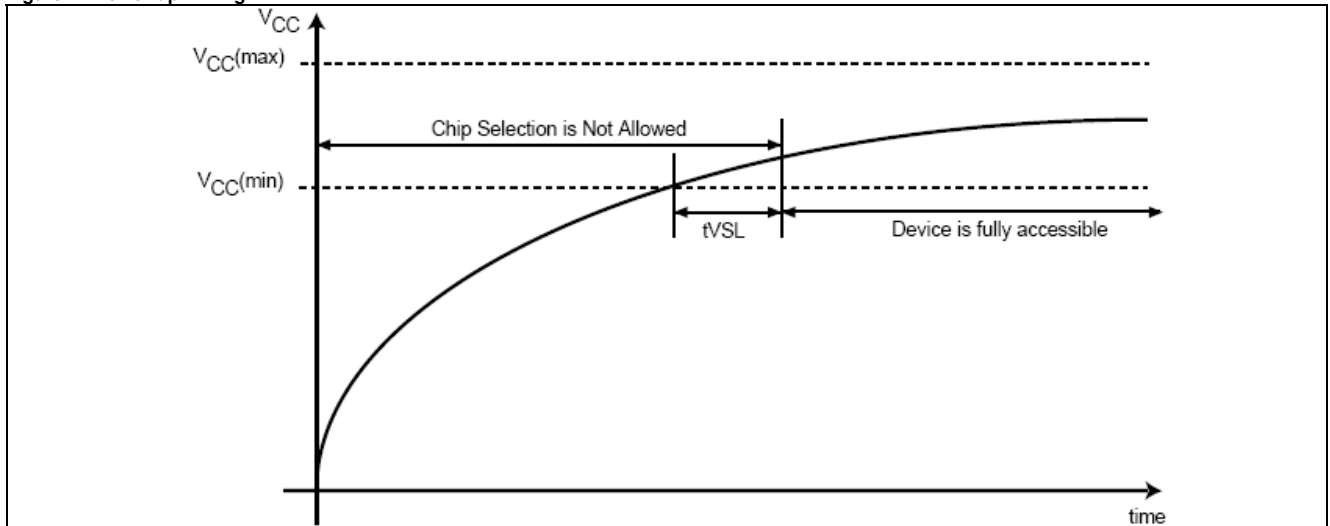
Figure26. Read Electronic Manufacturer & Device ID (REMS) Sequence (Command 90 or EF)



Notes:

- (1) ADD=00H will output the manufacturer's ID first and ADD=01H will output device ID first
- (2) Instruction is either 90(hex) or EF(hex).

Figure27. Power-up Timing



Note: VCC (max.) is 3.6V and VCC (min.) is 2.7V.

Table10. Power-Up Timing

Symbol	Parameter	Min.	Max.	Unit
tVSL(1)	VCC(min) to CS# low	200	-	us

Note: 1.The parameter is characterized only.

13. RECOMMENDED OPERATING CONDITIONS

13.1. At Device Power-Up

AC timing illustrated in Figure A is recommended for the supply voltages and the control signals at device power-up. If the timing in the figure is ignored, the device may not operate correctly.

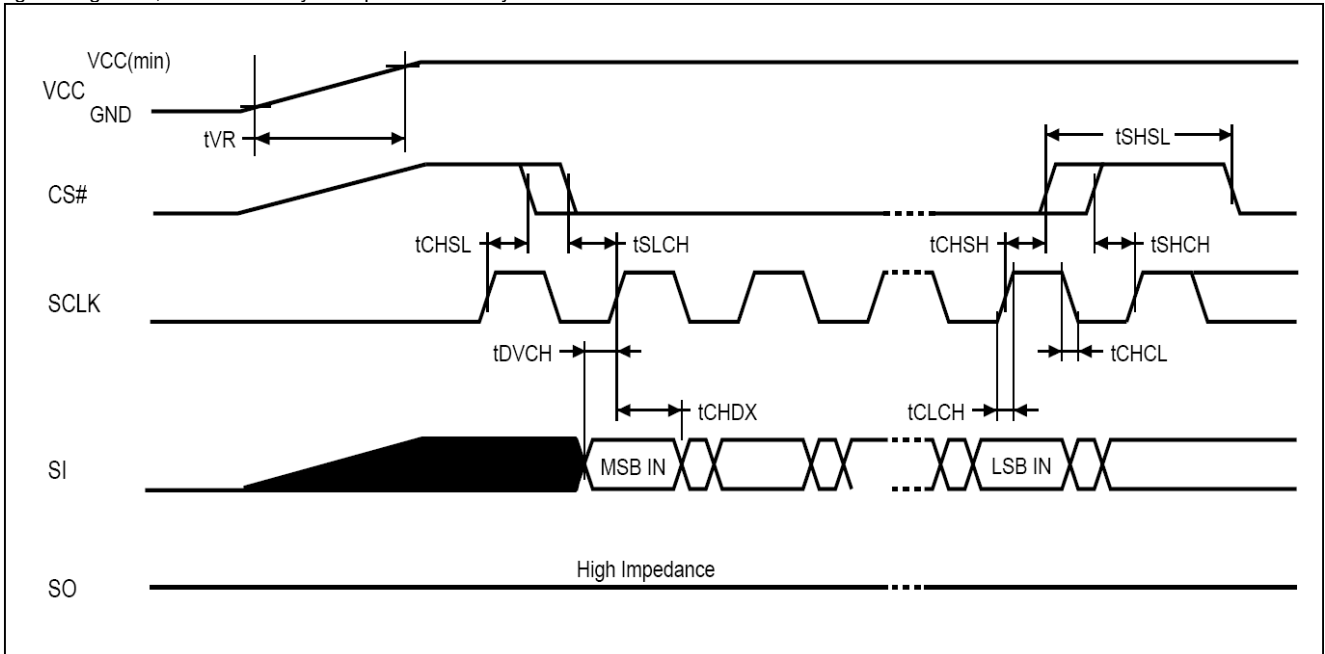


Figure A. AC Timing at Device Power-Up

Symbol	Parameter	Notes	Min.	Max.	Unit
tVR	VCC Rise Time	1	20	500000	us/V

Notes:

1. Sampled, not 100% tested.
2. For AC spec tCHSL, tSLCH, tDVCH, tCHDX, tSHSL, tCHSH, tSHCH, tCHCL, tCLCH in the figure, please refer to "AC CHARACTERISTICS" table.

14. ERASE AND PROGRAMMING PERFORMANCE

Parameter	Min.	Typ. (1)	Max. (2)	Unit
Write Status Register Time	-	40	100	ms
Sector Erase Time	-	60	300	ms
Block Erase Time	-	0.7	2	s
Chip Erase Time	-	7	15	s
Byte Program Time (via page program command)	-	9	300	us
Page Program Time	-	1.4	5	ms
Erase/Program Cycle	-	100,000	-	cycles

Note:

1. Typical program and erase time assumes the following conditions: 25°C, 3.3V, and checker board pattern.
2. Under worst conditions of 85° C and 2.7V.
3. System-level overhead is the time required to execute the first-bus-cycle sequence for the programming command.
4. Erase/Program cycles comply with JEDEC JESD-47E & A117A standard.

14.1. Data Retention

Parameter	Condition	Min.	Max.	UNIT
Data retention	55°C	20	-	years

15. LATCH-UP CHARACTERISTICS

	Min.	Max.
Input Voltage with respect to GND on all power pins, SI, CS#	-1.0V	2 VCCmax
Input Voltage with respect to GND on SO	-1.0V	VCC + 1.0V
Current	-100mA	+100mA
Includes all pins except VCC. Test conditions: VCC = 3.0V, one pin at a time.		



16. PACKAGE/PAD LOCATIONS

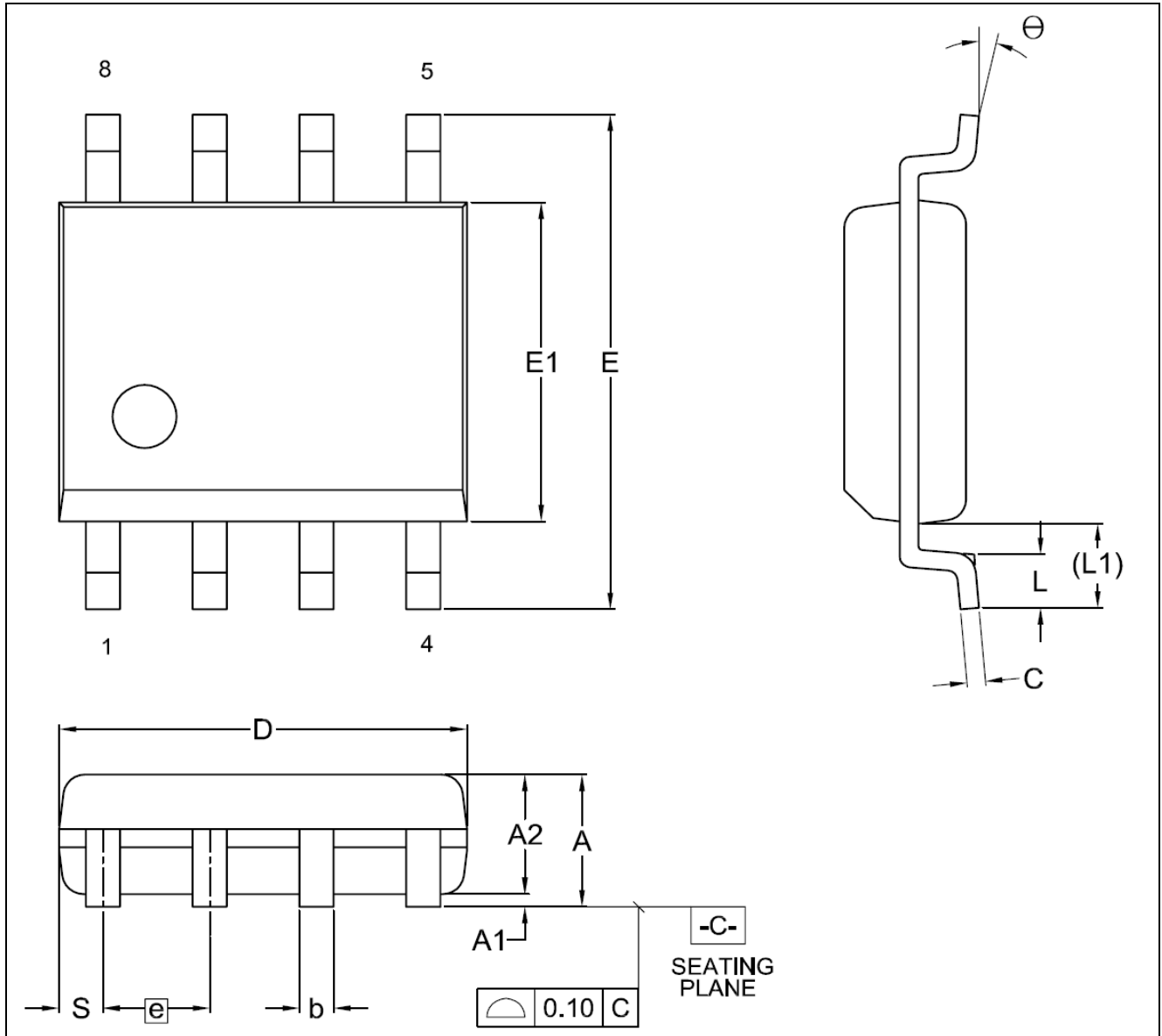
16.1. Ordering Information

Product Number	Package Type
GPR25L081B-QS01x	SOP 8L 150mil-Halogen Free Package

Note: x = 1 - 9, serial number.

16.2. Package Information

16.2.1. Package Outline for SOP 8L (150MIL)



16.2.1.1. Dimensions (Inch dimensions are derived from the original mm dimensions)

Symbol	A	A1	A2	b	C	D	E	E1	e	L	L1	S	θ
mm	Min.	0.10	1.35	0.36	0.15	4.77	5.80	3.80	-	0.46	0.85	0.41	0
	Nom.	0.15	1.45	0.41	0.20	4.90	5.99	3.90	1.27	0.66	1.05	0.54	5
	Max.	1.75	0.20	1.55	0.51	5.03	6.20	4.00	-	0.86	1.25	0.67	8
inch	Min.	0.004	0.053	0.014	0.006	0.188	0.228	0.150	-	0.018	0.033	0.016	0
	Nom.	0.006	0.057	0.016	0.008	0.193	0.236	0.154	0.050	0.026	0.041	0.021	5
	Max.	0.069	0.008	0.061	0.020	0.198	0.244	0.158	-	0.034	0.049	0.026	8

DWG. NO.	Revision	Reference		Issue Date
		JEDEC	EIAJ	
6110-1401	6	MS-012	-	11-26-03

17. DISCLAIMER

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18. REVISION HISTORY

Date	Revision	Description	Page
Dec. 15, 2010	1.1	Add writer compatible information in section 1.1	4
Mar. 19, 2010	1.0	Original	38